



2026 Semiconductor Simulation Trend

3DL Q3D/HBM/TSV/Microbump

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Senior Architect

Agenda

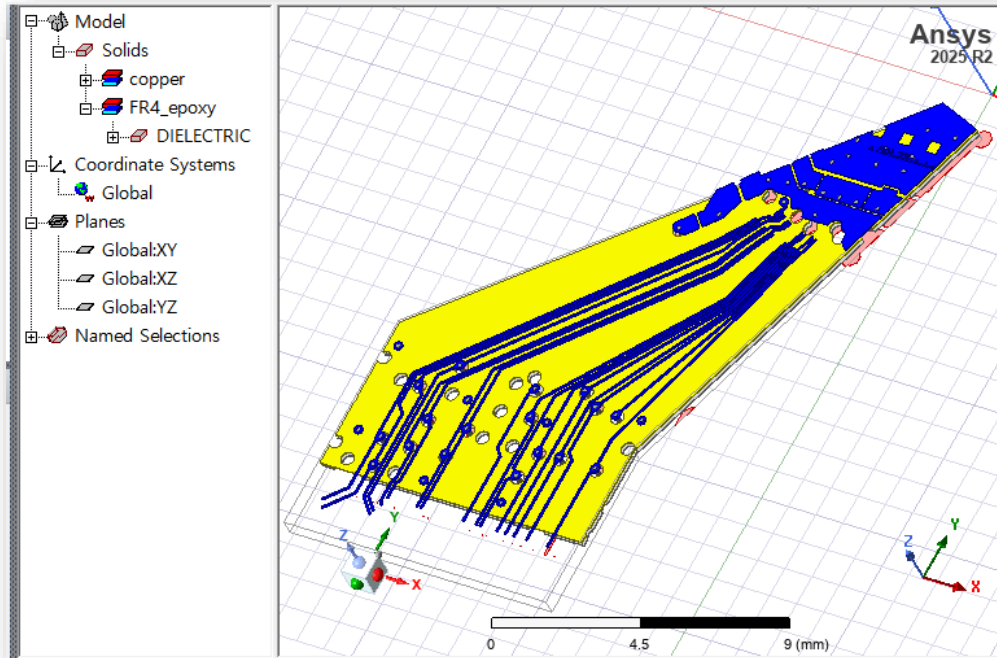
- **Q3D in 3D Layout : Pros & Cons**
- **TSV array simulation & automation**
- **Microbump thermal simulation**

Q3D in 3D Layout :

Pros & Cons

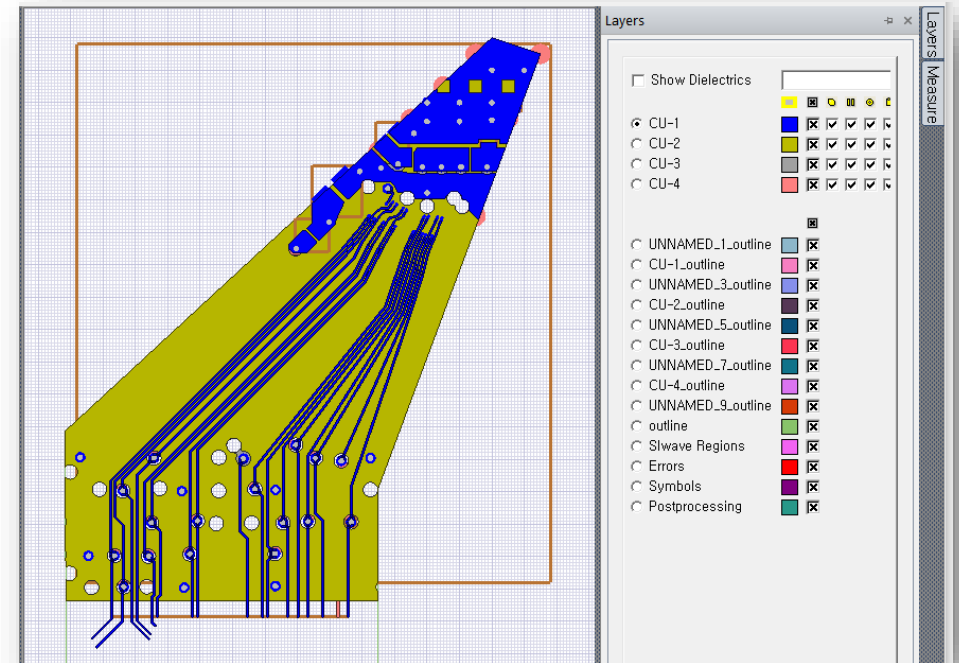


MCAD Q3D vs. 3DL Q3D



MCAD Q3D

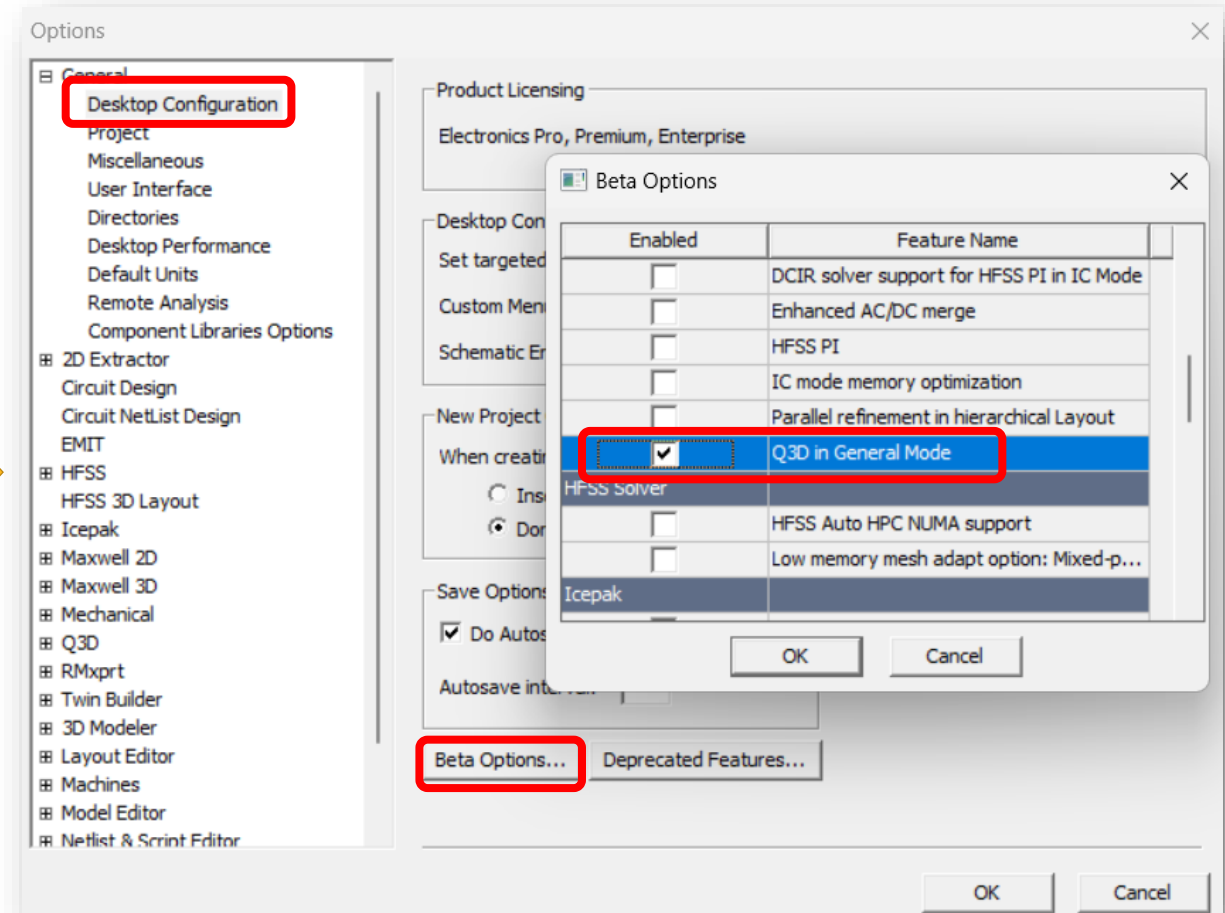
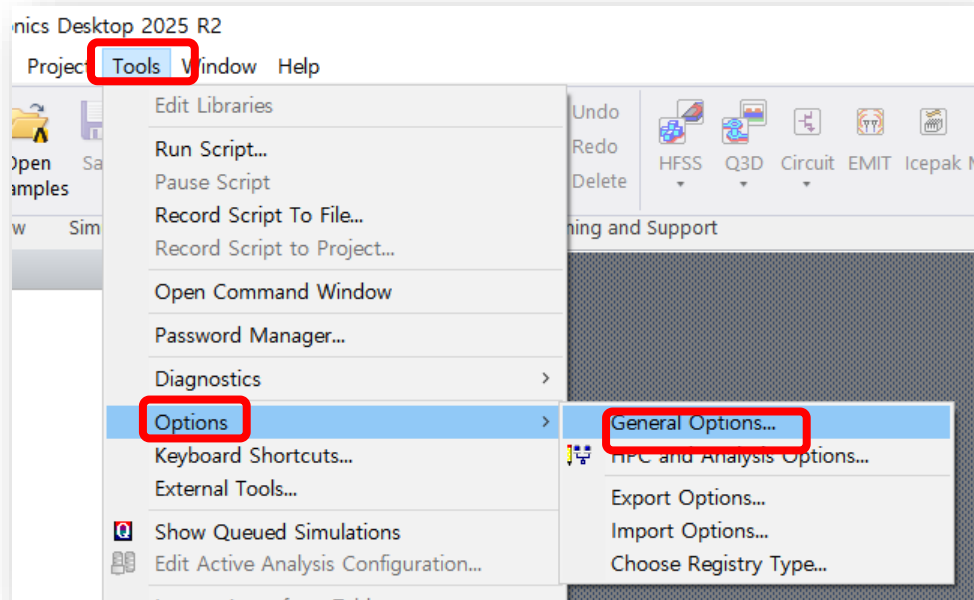
- Conventional Full 3D modeling based on [Parasolid 3D modeler](#)



Q3D in 3D Layout

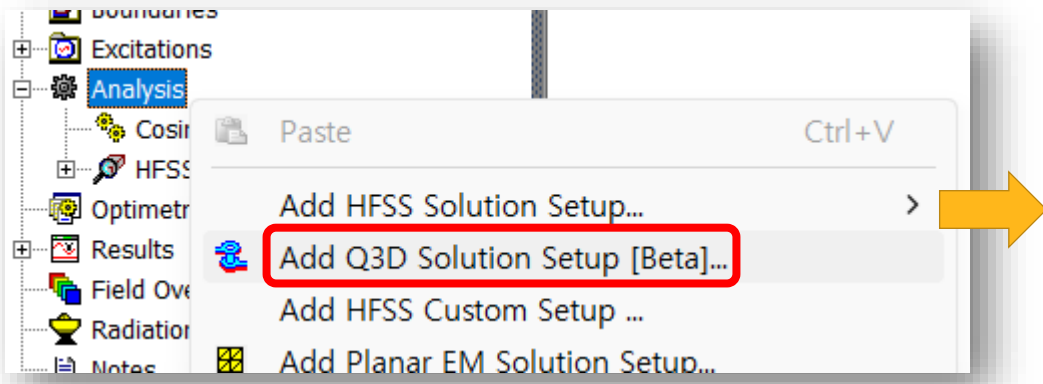
- PCB/PKG only with Net & Layer based on [ECAD viewer](#)

STEP 1 : Q3D in General Mode Setup (Beta)

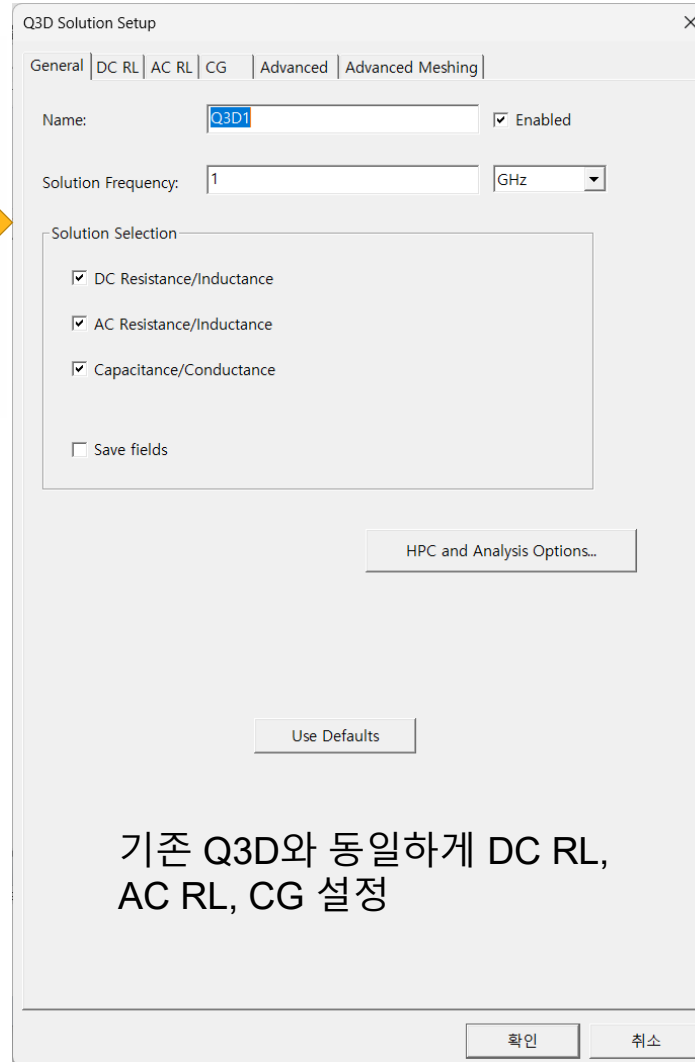


- IC mode에서는 정식 기능
- General mode에서는 Beta 기능으로서, Option에서 활성화시켜야 사용 가능

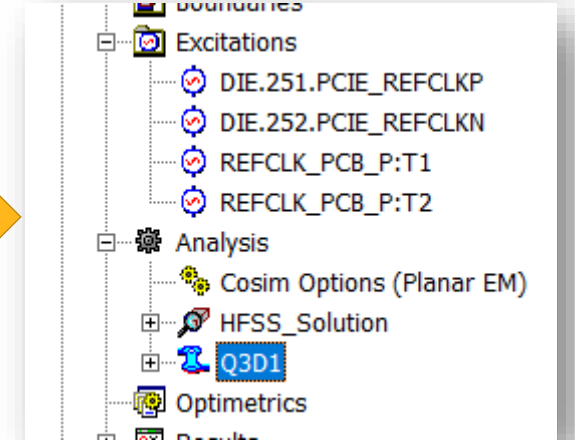
STEP 2 : HFSS 3D Layout - Q3D Setup 추가



Analysis에서 Q3D setup 추가

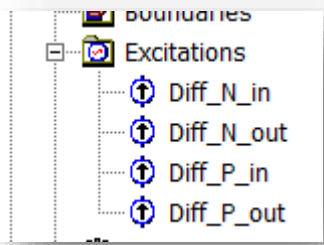


기존 Q3D와 동일하게 DC RL,
AC RL, CG 설정

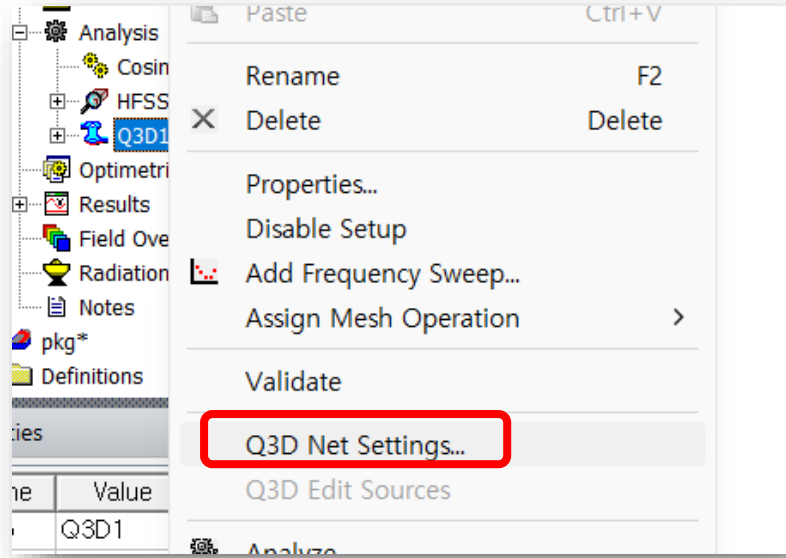


Q3D setup 생성

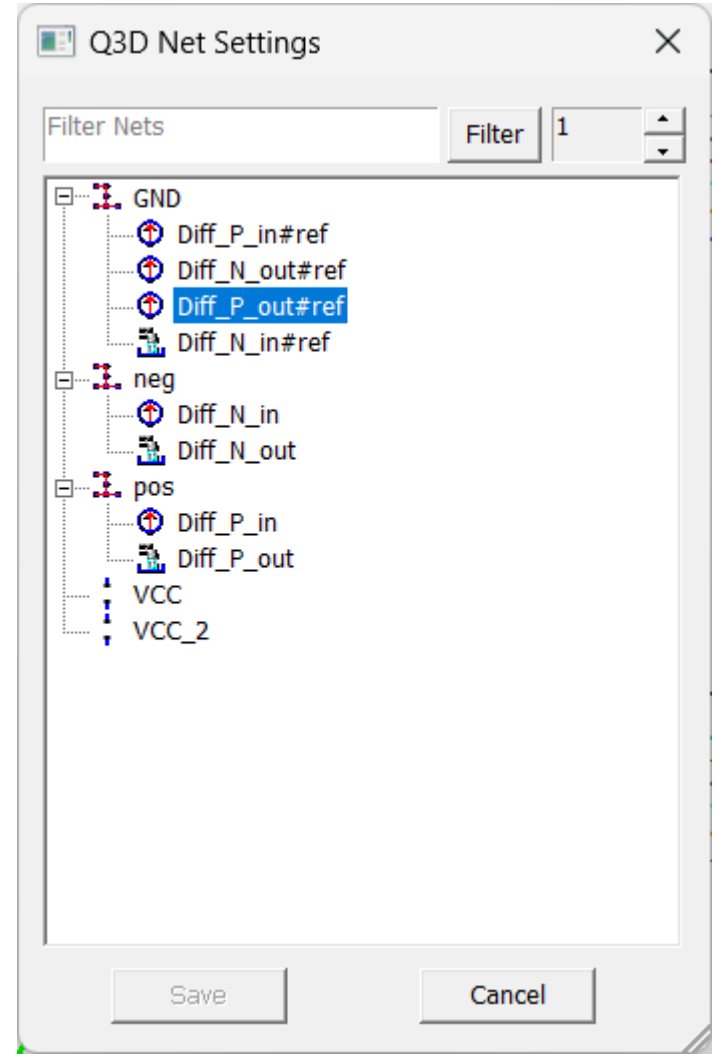
STEP 3 : Q3D net (source/sink) 설정 in HFSS 3D Layout



HFSS Port 설정

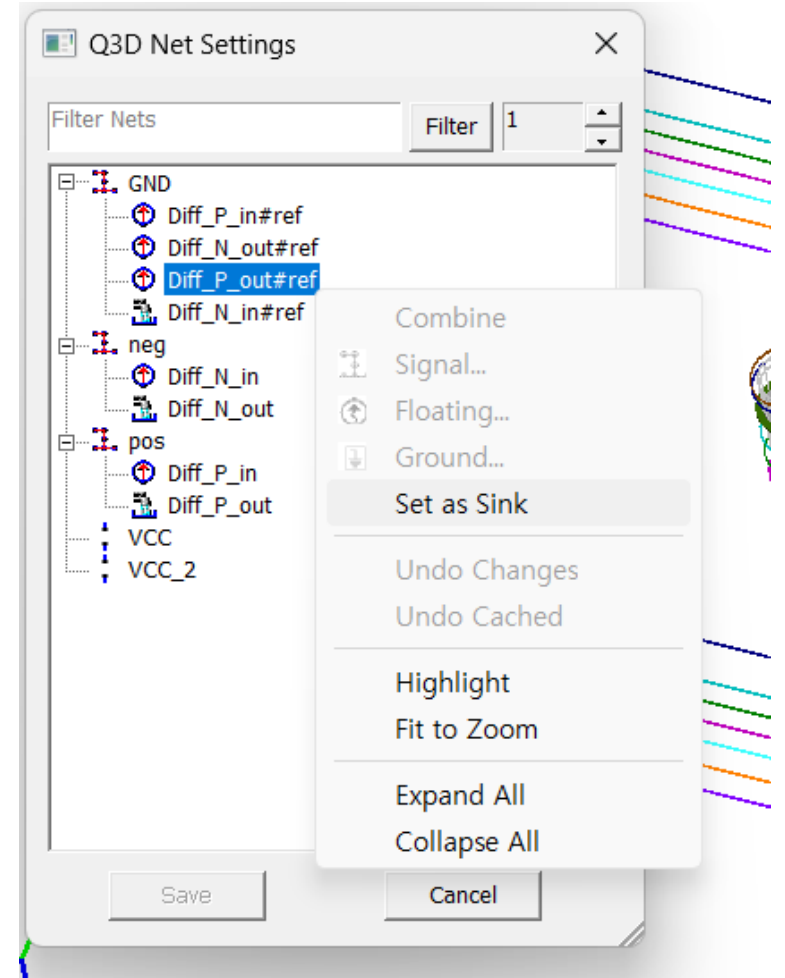
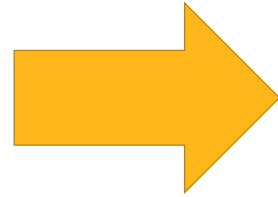
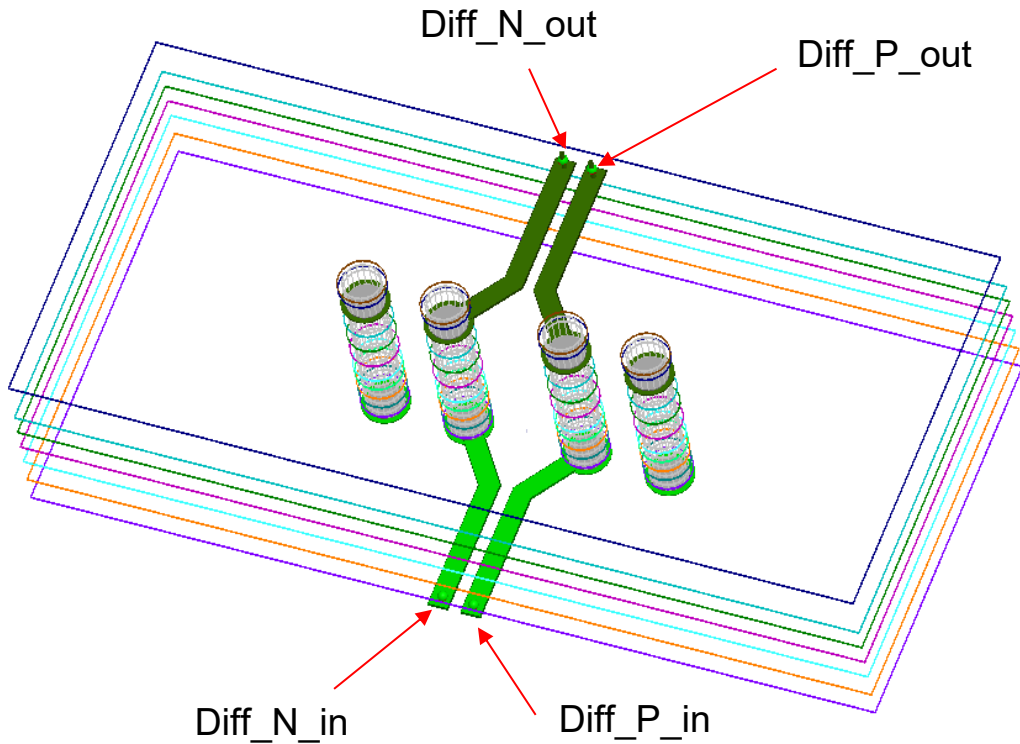


Q3D setup에서 우클릭 →
Q3D Net Seetings



HFSS Port terminal을 기준으로
자동으로 source/sink와 net이 설정됨

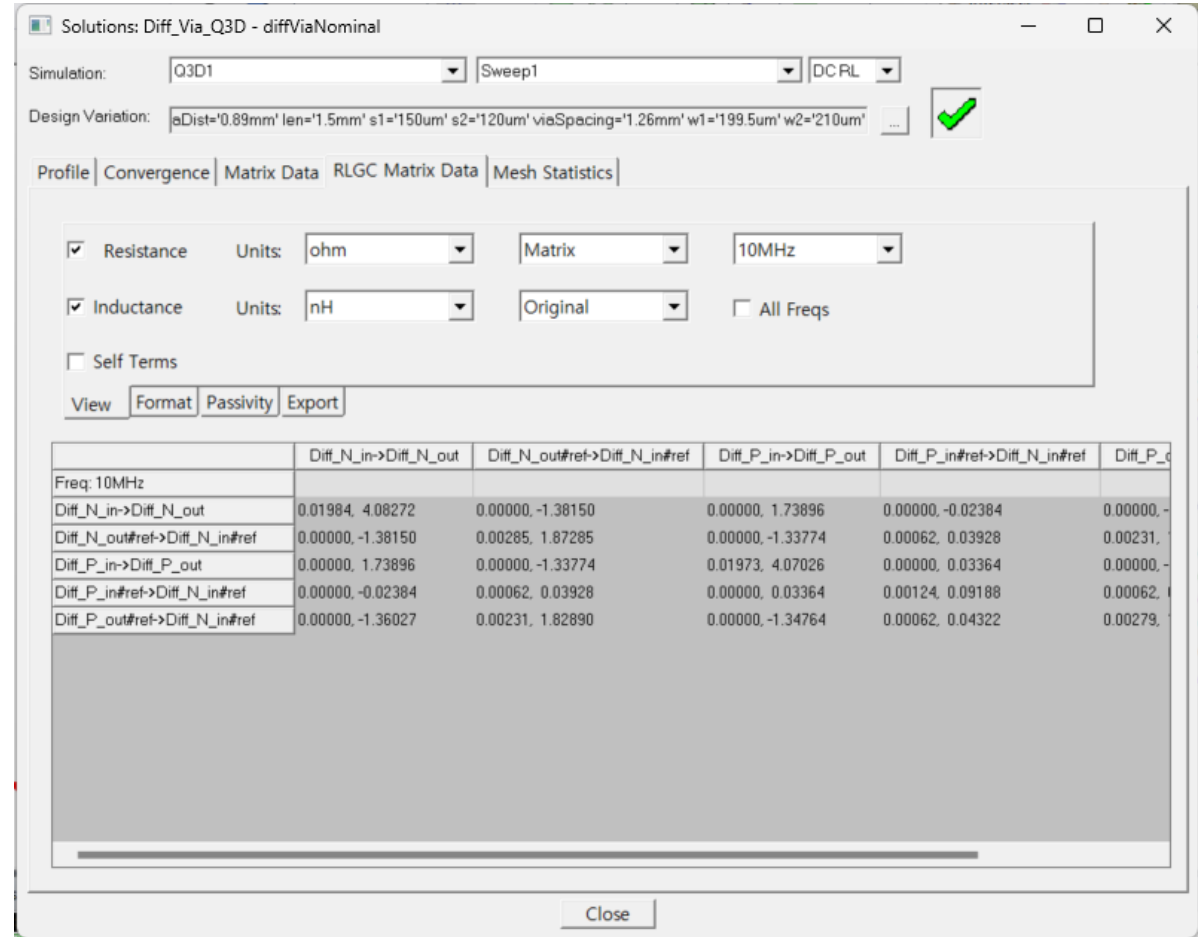
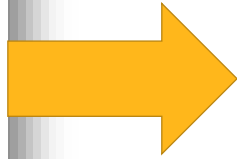
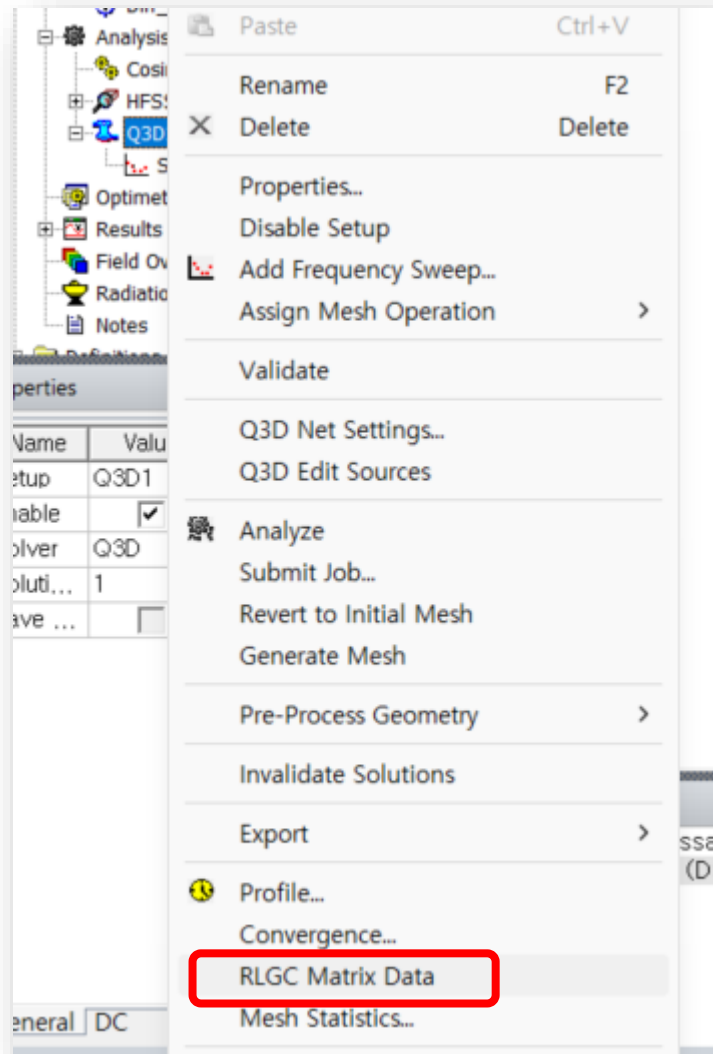
STEP 4 : Automatic Source/Sink Assign & modifying



User가 source/sink를 변경 가능

- 미리 생성된 HFSS Port 를 기준으로
- Signal net 시작과 끝에 자동으로 source/sink 배치
- 공통 Reference net에 1개의 sink와 나머지는 source 자동 배정
- Wave port는 불가능, terminal과 lumped port만 가능

STEP 5 : RLGC Result

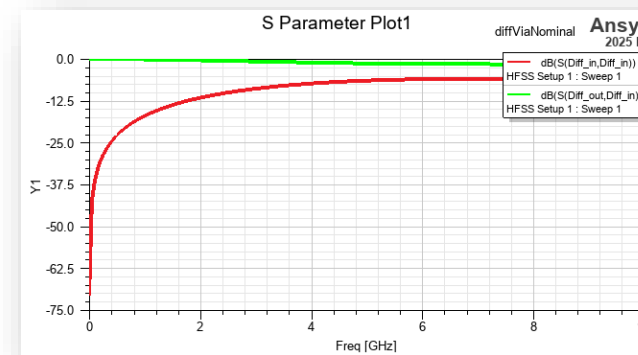
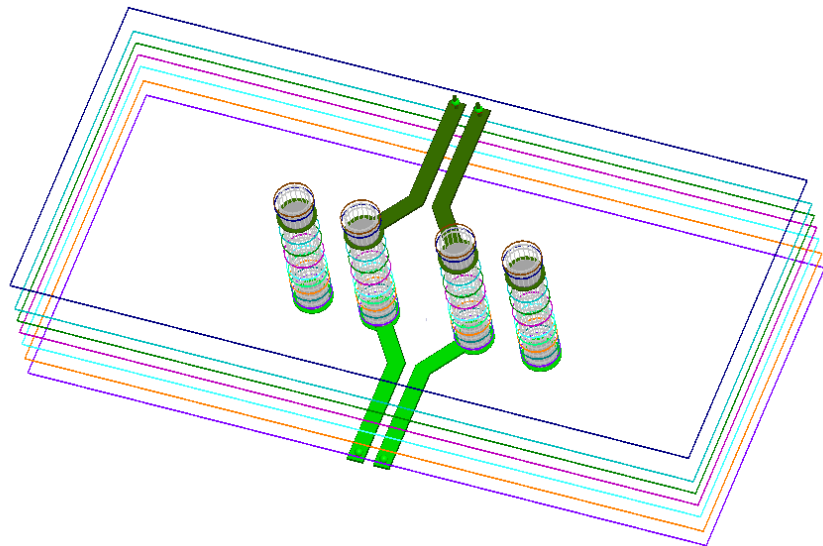


- RLGC 결과를 확인하는 방법은 기존 Q3D와 동일

Q3D in HFSS 3D Layout 의 장점

1. HFSS 를 위한 모델과 셋업 그대로 즉시 Q3D solver를 돌릴 수 있음
- 별도로 Q3D export 및 source/sink modeling이 필요 없음
2. HFSS 3D Layout 특유의 빠르고 가벼운 GUI를 활용할 수 있음
- 복잡하고 큰 모델의 경우, 기존의 Q3D보다 작업효율이 크게 개선됨
3. Intersection check와 Finding Net 과정이 생략되어 해석속도 증가

→ 동일한 모델로 한꺼번에 HFSS S parameter와 Q3D RLGC 데이터를 추출 가능



Freq: 10MHz	Diff_N_in->Diff_N_out	Diff_N_out#ref->Diff_N_in#ref	Diff_P_in->Diff_P_out	Diff_P_in#ref->Diff_N_in#ref	Diff_P_out#ref->Diff_N_in#ref
Diff_N_in->Diff_N_out	0.01984, 4.08272	0.00000, -1.38150	0.00000, 1.73896	0.00000, -0.02384	0.00000, -1.36027
Diff_N_out#ref->Diff_N_in#ref	0.00000, -1.38150	0.00285, 1.87285	0.00000, -1.33774	0.00062, 0.03928	0.00231, 1.82890
Diff_P_in->Diff_P_out	0.00000, 1.73896	0.00000, -1.33774	0.01973, 4.07026	0.00000, 0.03364	0.00000, -1.34764
Diff_P_in#ref->Diff_N_in#ref	0.00000, -0.02384	0.00062, 0.03928	0.00000, 0.03364	0.00124, 0.09188	0.00062, 0.04322
Diff_P_out#ref->Diff_N_in#ref	0.00000, -1.36027	0.00231, 1.82890	0.00000, -1.34764	0.00062, 0.04322	0.00279, 1.86597

MCAD Q3D vs. 3DL Q3D : Detail Comparison

	MCAD Q3D	3DL Q3D	3DL Workaround
Result/Terminal	RLC extraction only based on 2D source/sink	RLC extraction & HFSS/Slwave sim based on port	
GUI rendering	Slow (Full 3D)	Super-fast (ECAD)	
Intersection check	Yes (can be minimized)	No need	
Finding net process	Yes (can be ignored)	No need	
tan δ + Conductivity Setup	Possible	No	tan δ compensation
Automation script	100% support	80% support	Hard coding
Accuracy	Golden Standard	To be correlated	
Simulation Speed		About 10~50% faster	



Silicon is semiconductor..

MCAD Q3D

3DL Q3D

Material Name
silicon

Properties of the Material

Name	Type	Value	Units
Relative Permittivity	Simple	11.9	
Relative Permeability	Simple	1	
Bulk Conductivity	Simple	15	siemens/m
Dielectric Loss Tangent	Simple	0	

Material Name
silicon_3DL

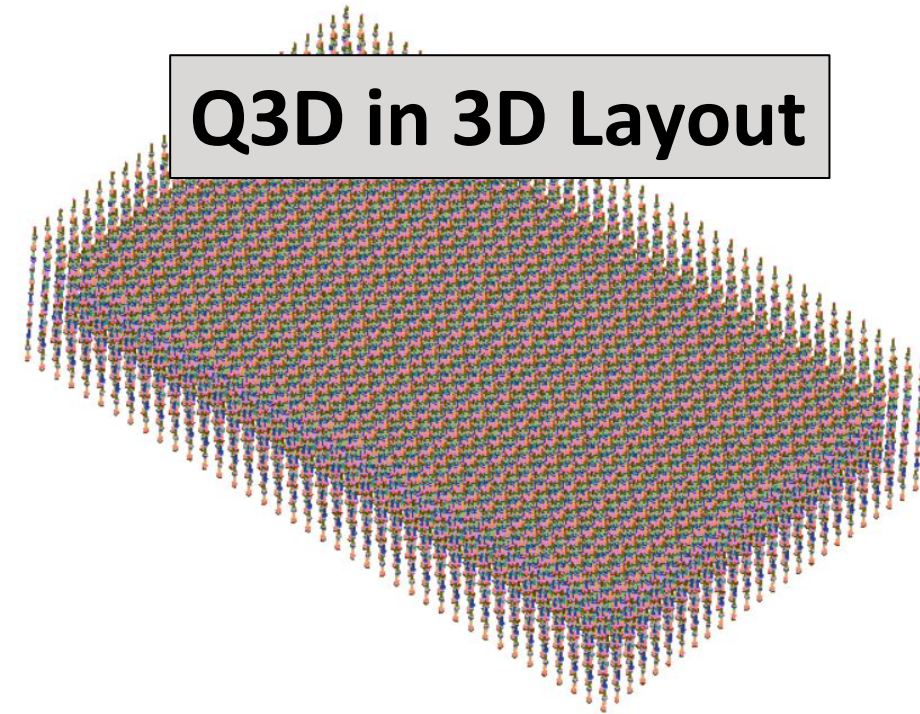
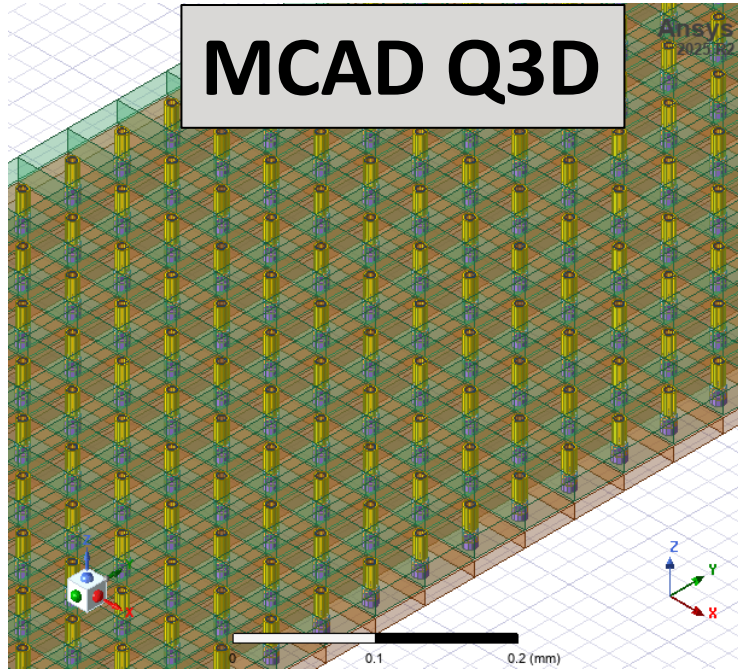
Properties of the Material

Name	Type	Value	Units
Relative Permittivity	Simple	11.9	
Relative Permeability	Simple	1	
Bulk Conductivity	Simple	0	siemens/m
Dielectric Loss Tangent	Simple	10/(2*pi*freq)	

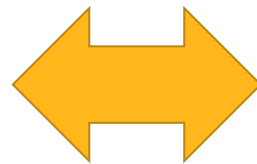
$$\epsilon_{\text{eff}} = \epsilon' - j(\epsilon' \cdot \tan \delta + \sigma/\omega)$$

- User can set Dielectric property and conductivity at the same time in MCAD Q3D
- Conductivity works as a loss term and effects to G(Transconductance) value
- User can set loss tangent with conductivity in the 3DL Q3D

Key Summary : MCAD Q3D vs. 3DL Q3D

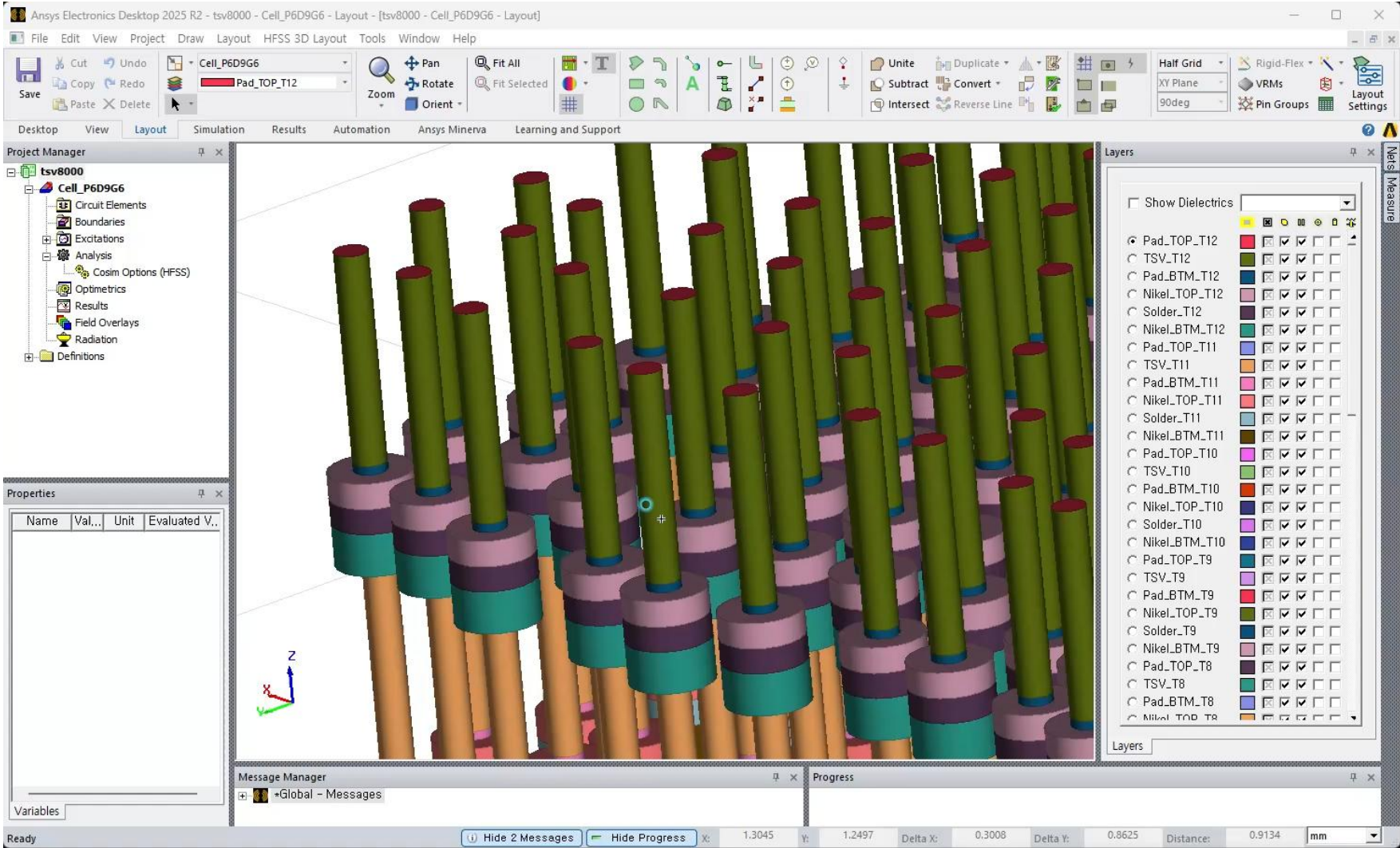


- Golden Standard
- Set loss tangent + conductivity : possible
- Stable automation (IPY script, PyAEDT)
- Long finding net / intersection check time
- Slow GUI rendering

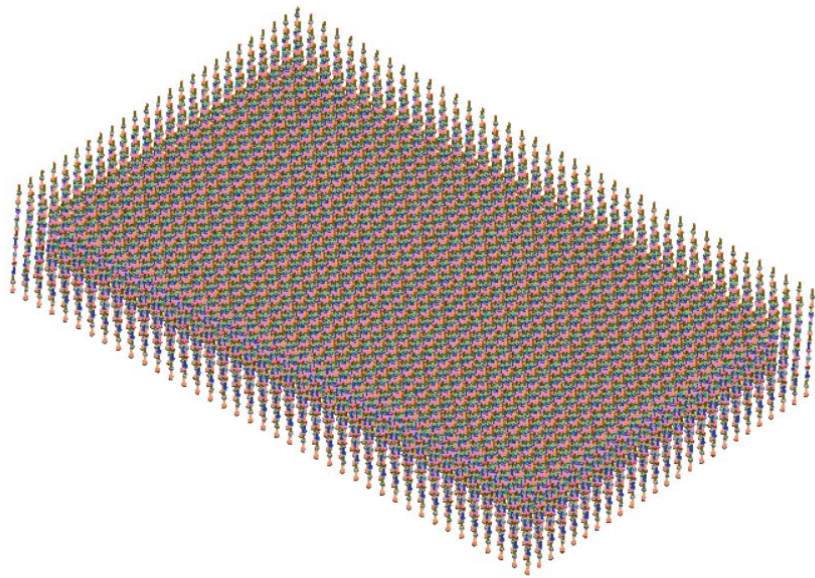


- To be correlated to MCAD Q3D result
- Set loss tangent + conductivity : Work around
- beta automation (PyEDB) : Work around
- No finding net / intersection check
- Super fast GUI rendering

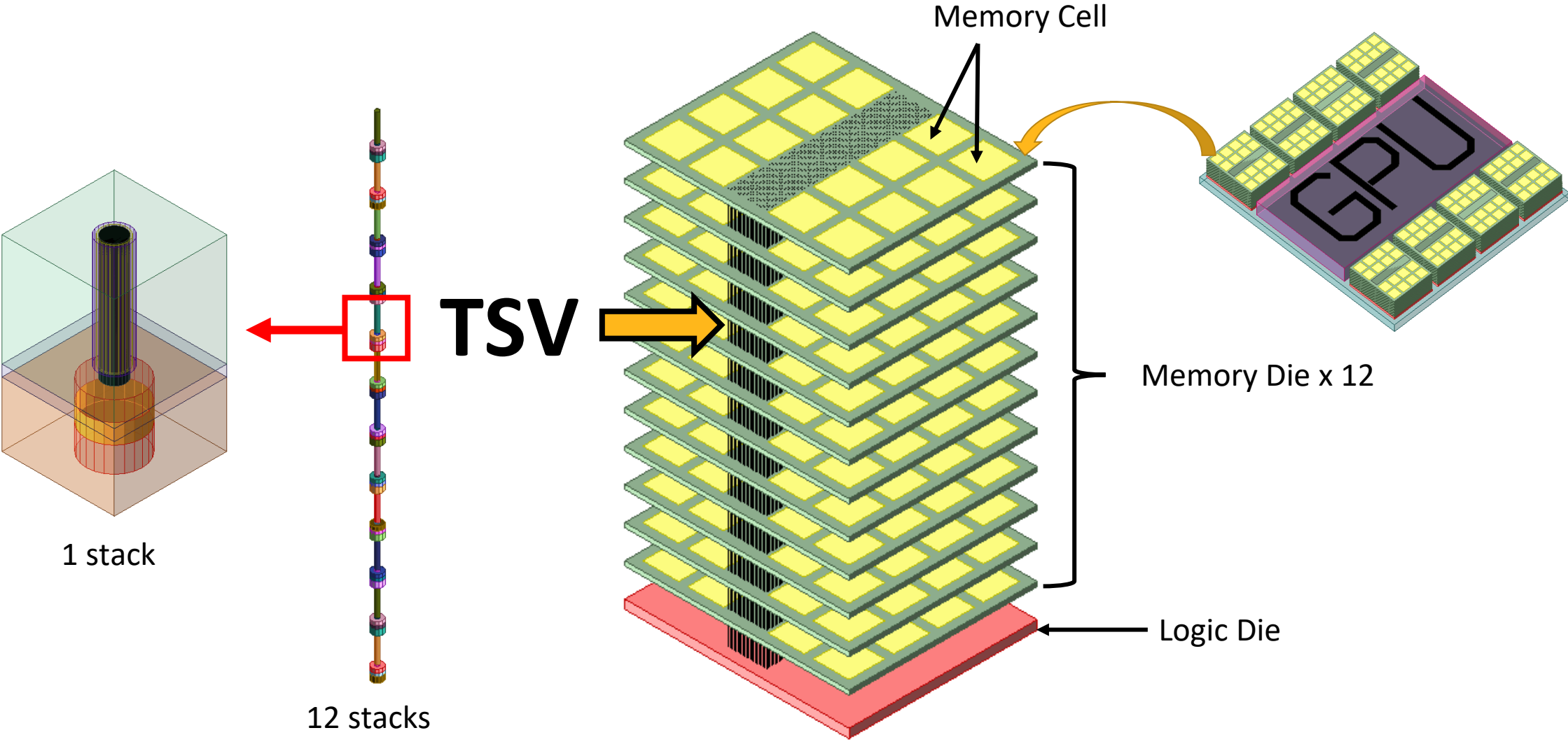
3DL Q3D : Super-fast GUI



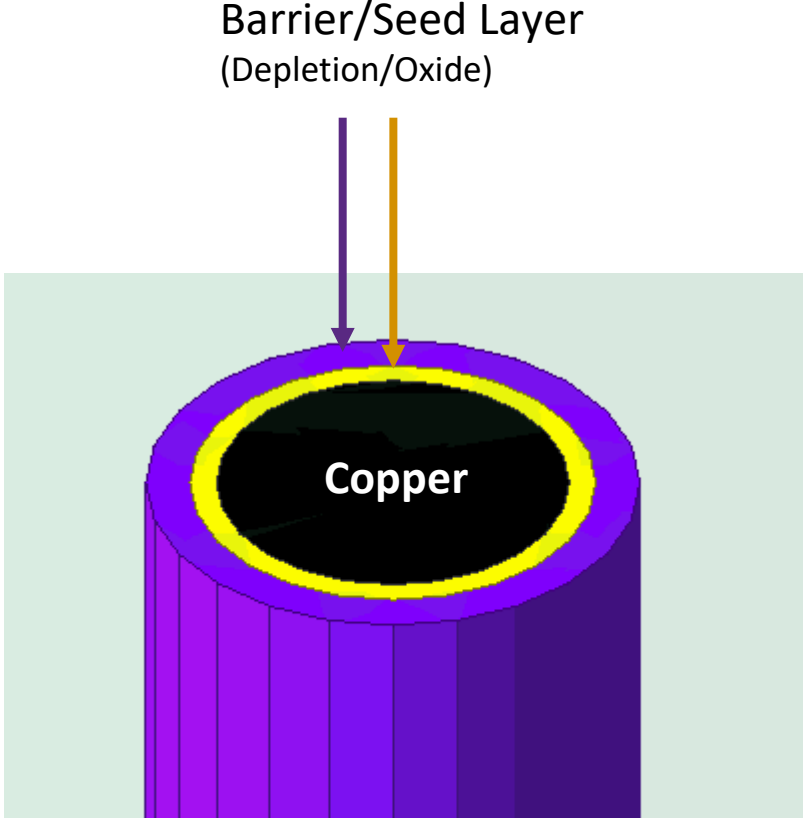
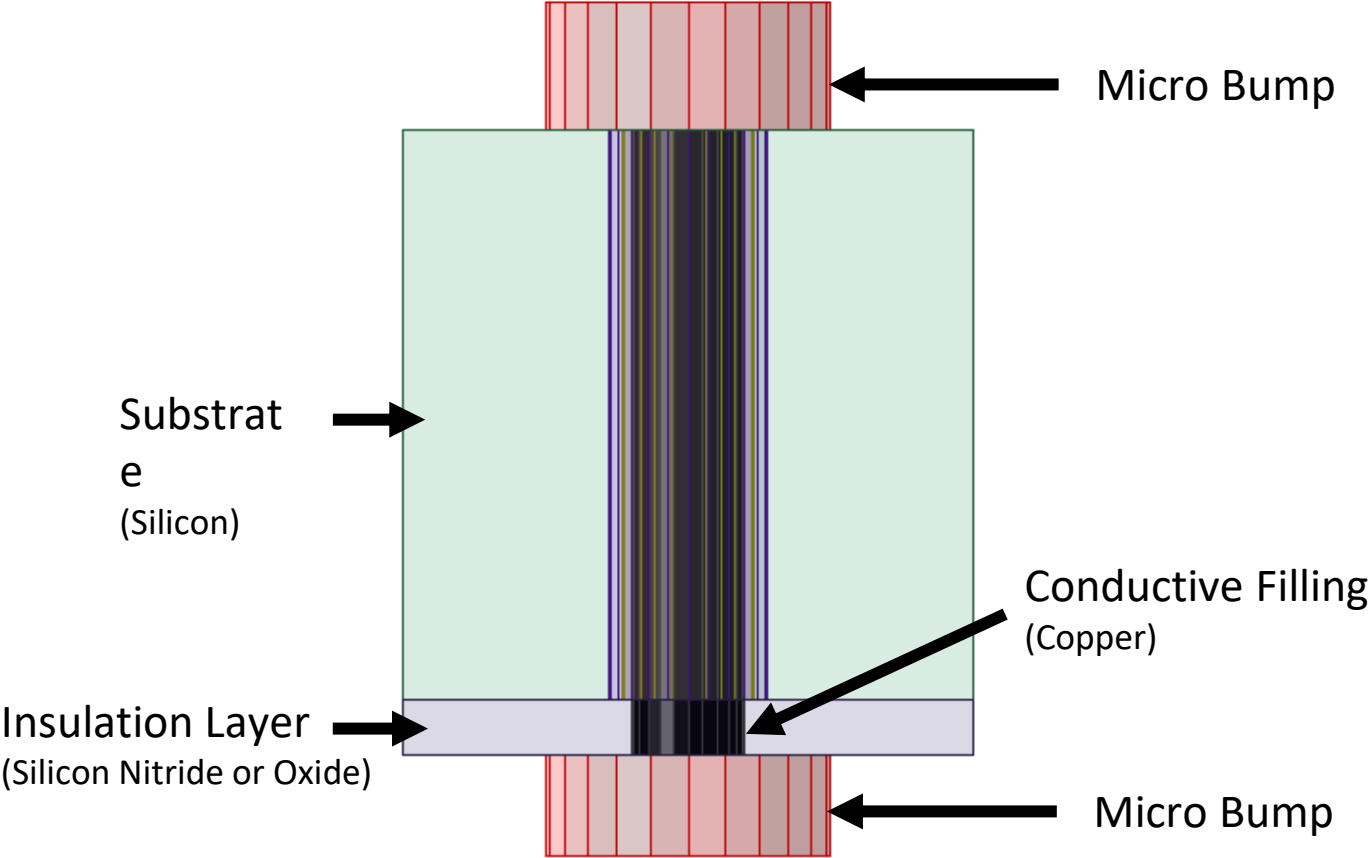
HBM TSV array simulation



TSV in HBM4

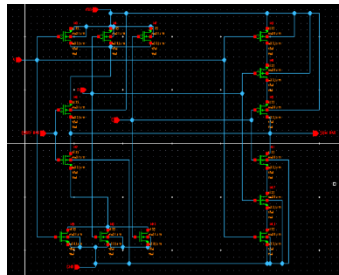
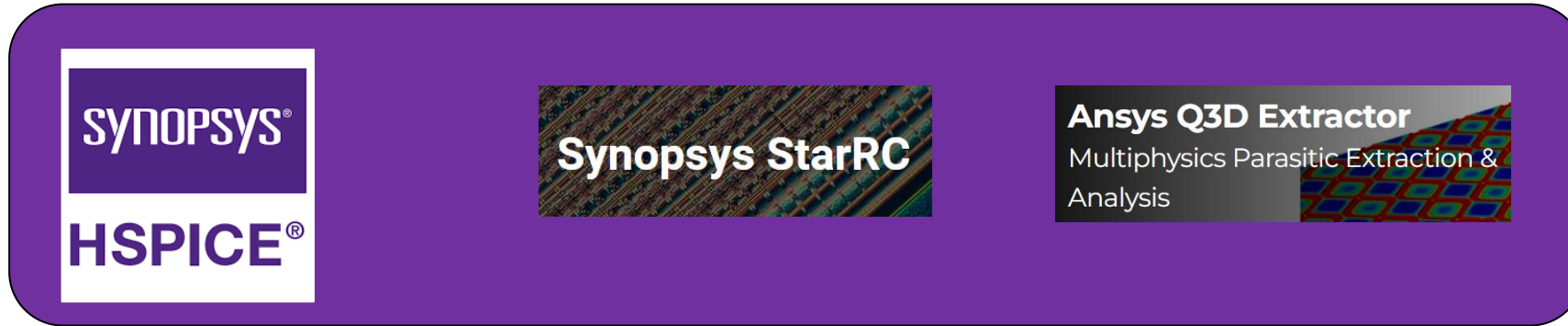


TSV(Through Silicon Via)



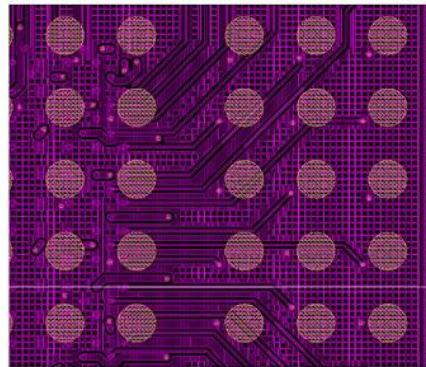
HBM SI sign-off with RLC parasitic

All Synopsys Products



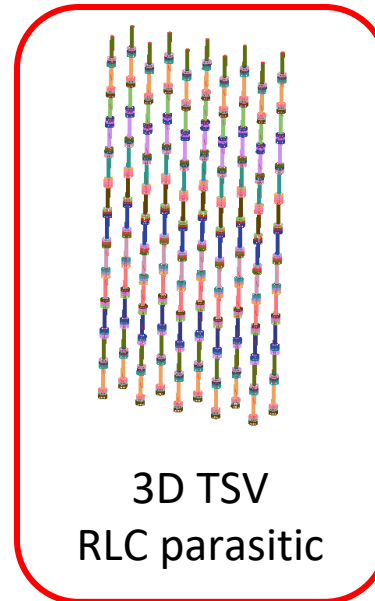
Schematic/Netlist
Circuit

+

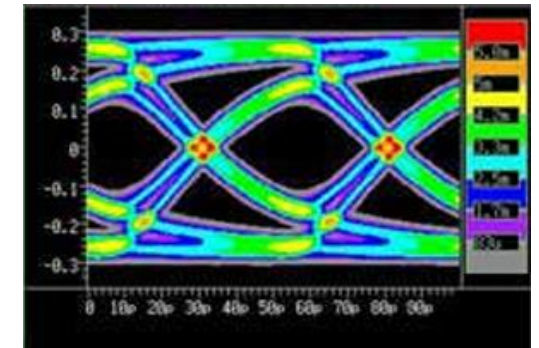
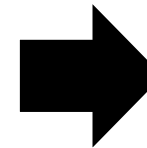


2.5D Die Layout
RLC parasitic

+



3D TSV
RLC parasitic



DDR EYE sign-off

3Dblox 2.0 for Synopsys 3DIC compiler

- **3DFabric** : CoWoS, InFO, SoIC brand name of TSMC
- **3Dblox 2.0** : HBM Design Rule Set for Sign off (a.k.a Integra)
- 3Dblox 2.0 consists of 5 Parts.

1. Power & Thermal Reliability

2. Physical & Logical Connectivity

3. SI/PI

- IR drop, Thermal-aware PI

- Extraction : RLC extraction from TSV, Micro-bump, RDL

- Insertion loss & Return loss

4. Static Timing Analysis

5. Structural Integrity & ESD

3Dblox official site in IEEE (<https://sagroups.ieee.org/>)

IEEE.org | IEEE Xplore® | IEEE Standards | IEEE Spectrum | More Sites

IEEE SA
STANDARDS
ASSOCIATION

3Dblox-- Chiplet Connectivity and Physical Properties Description Language

Home Meetings Members Subscribe

Title: Standard for 3Dblox-Chiplet Connectivity and Physical Properties Description Language

Scope: This standard defines a modular hierarchical language syntax, rules, and usage model to represent a high-level description of the components and connectivity between various components (including chiplets, interposers, substrates, etc.) in 2.5D/3D advanced packaging technologies. This description language enhances the 3Dblox description language. For each component, a high-level description includes size, orientation, interface, thickness, interconnect regions, interconnect structures, and other physical properties required for integration in a 2.5D/3D stack. The features of this description language are designed to serve chiplet makers, 2.5D/3D packagers, and end users.

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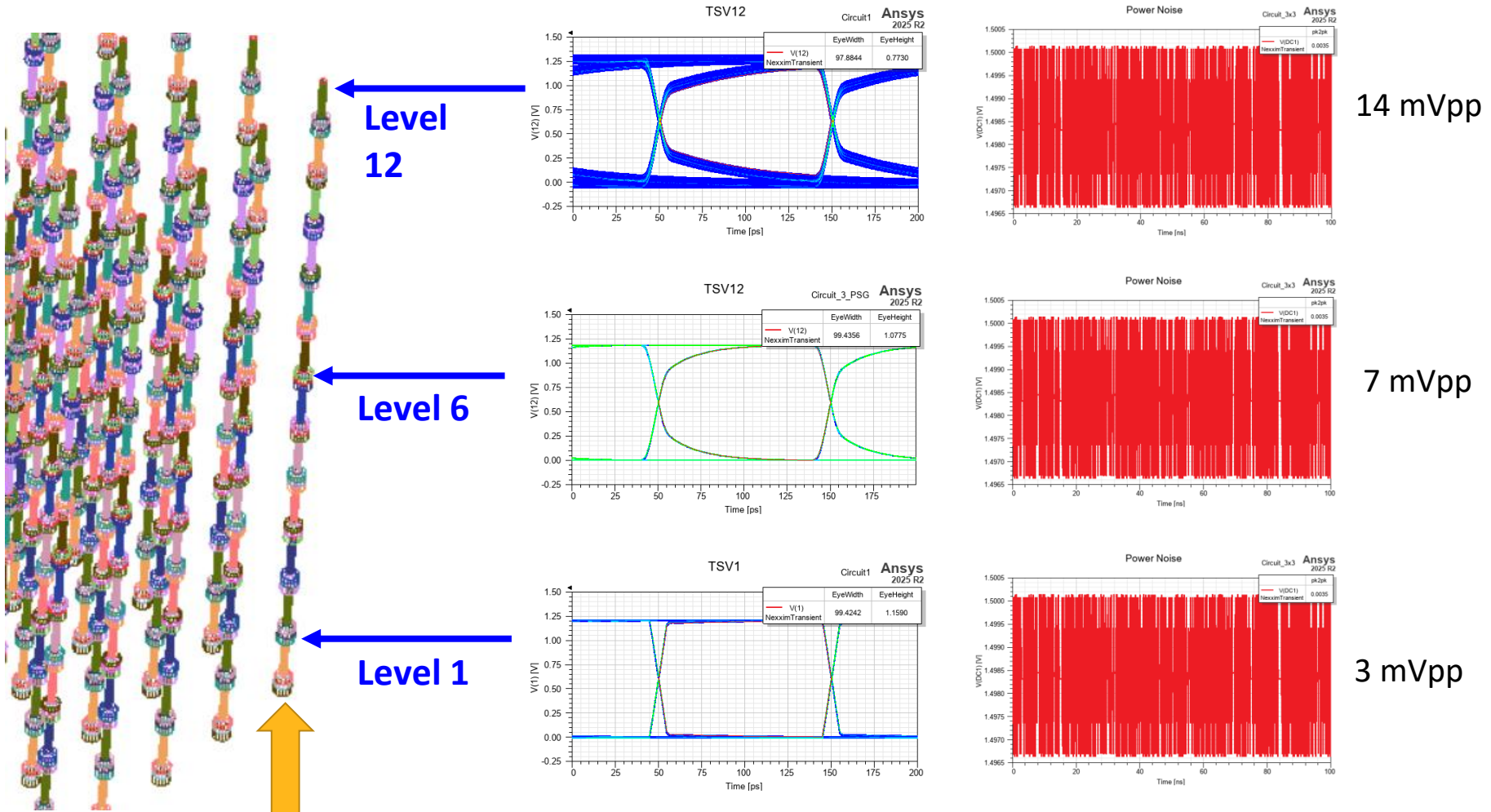
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Challenges : TSV design for HBM

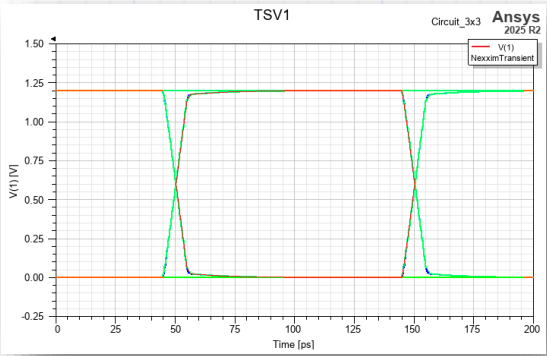
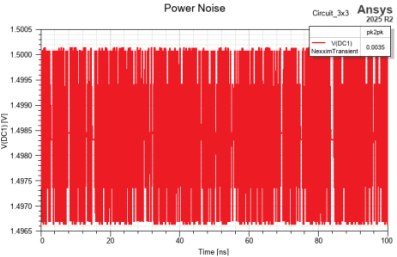
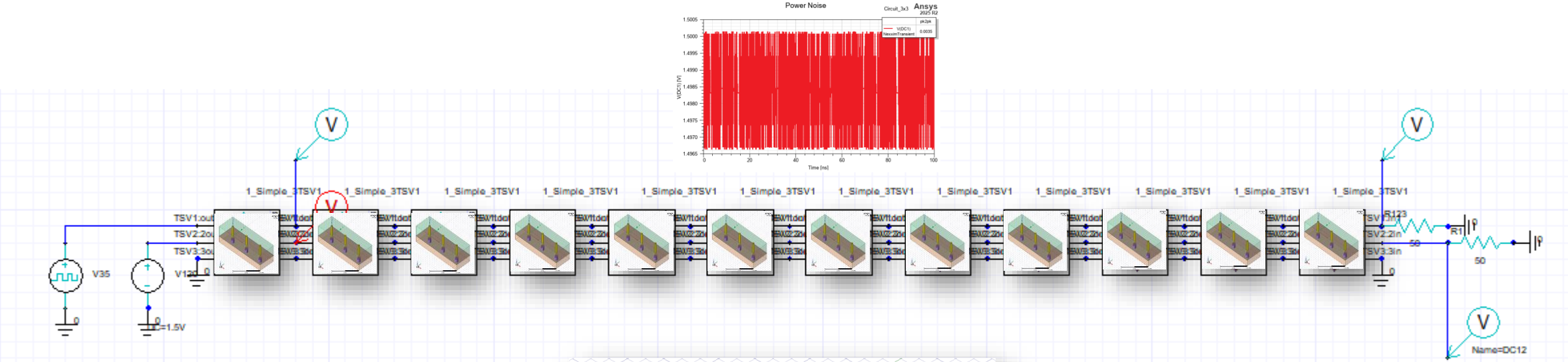
- **Too many TSVs**
 - HBM4 has over 8000 TSV with 12stacks
 - Burden of modeling, slow GUI rendering
 - Too long analysis time
 - slow and time-consuming post-process.
- **Optimum TSV assignment**
 - What is optimum assignment of Signal, Power, GND ?
 - How to optimize TSV assignment ?
- **What is the Key performance ?**
 - EYE & timing margin
 - SSN
 - TSV inductance

HBM4 TSV : Power noise (SSN) Issue

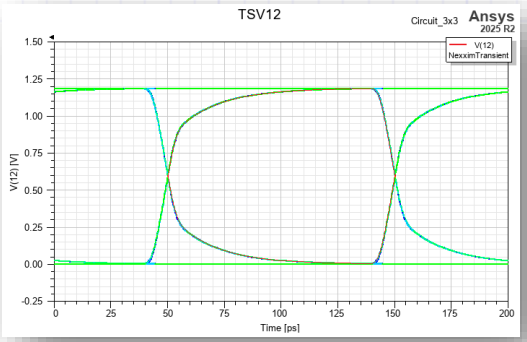
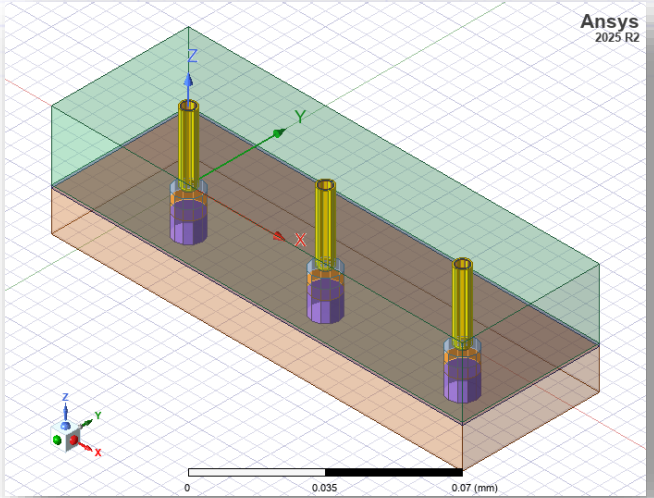


- High level node of TSV shows worse performance (DQ timing margin, SSN) due to increased **total inductance** through TSV path.

SSN test with 12stack TSV



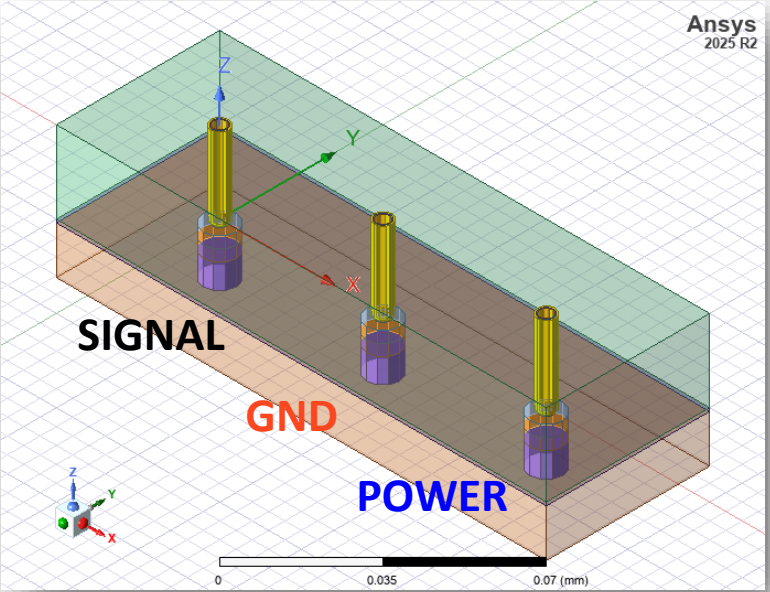
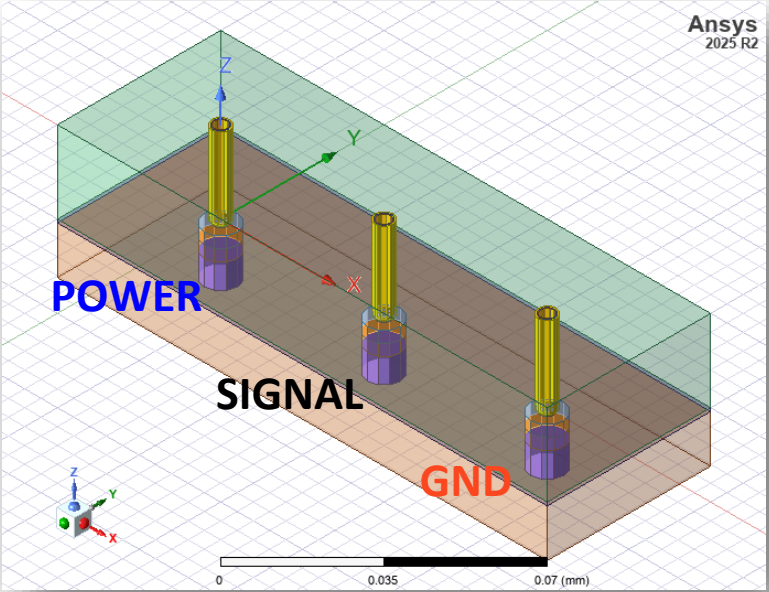
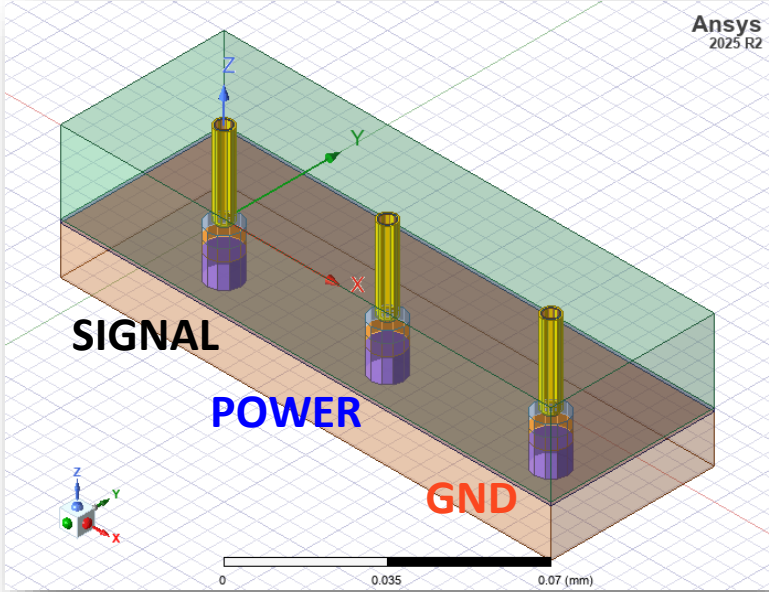
Level 1



Level 12



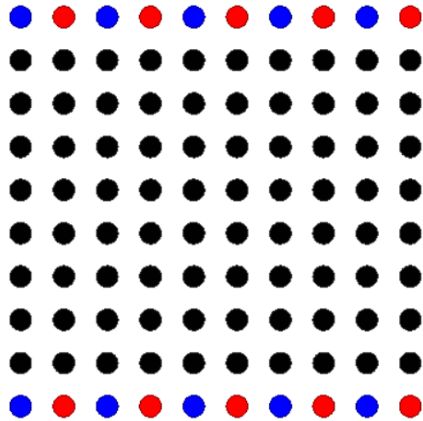
SSN test with 12stack TSV : Result



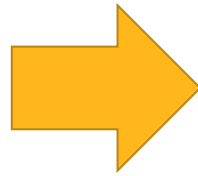
Unit : mVpp	S-P-G	P-S-G	S-G-P
Level 1 Power ripple	3.5	3.5	1.9
Level 12 Power ripple	14.5	14.7	4.5

Optimum Pin Array (Example)

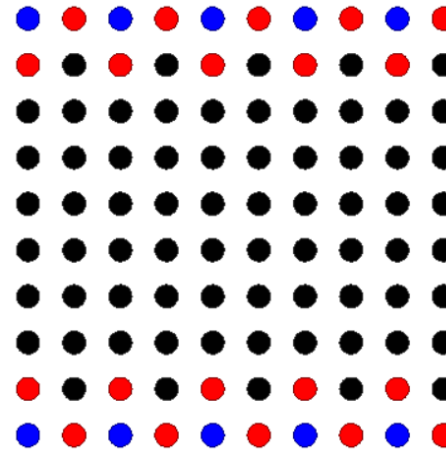
Minimum PDN



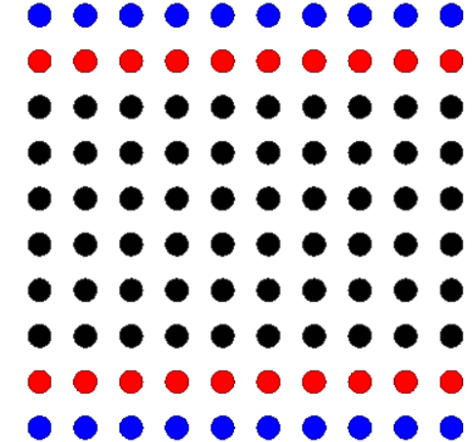
- P/G : 10% of total



S-G-P Ground guard



- P/G : 15% of total



- P/G : 20% of total

● Signal

● Power

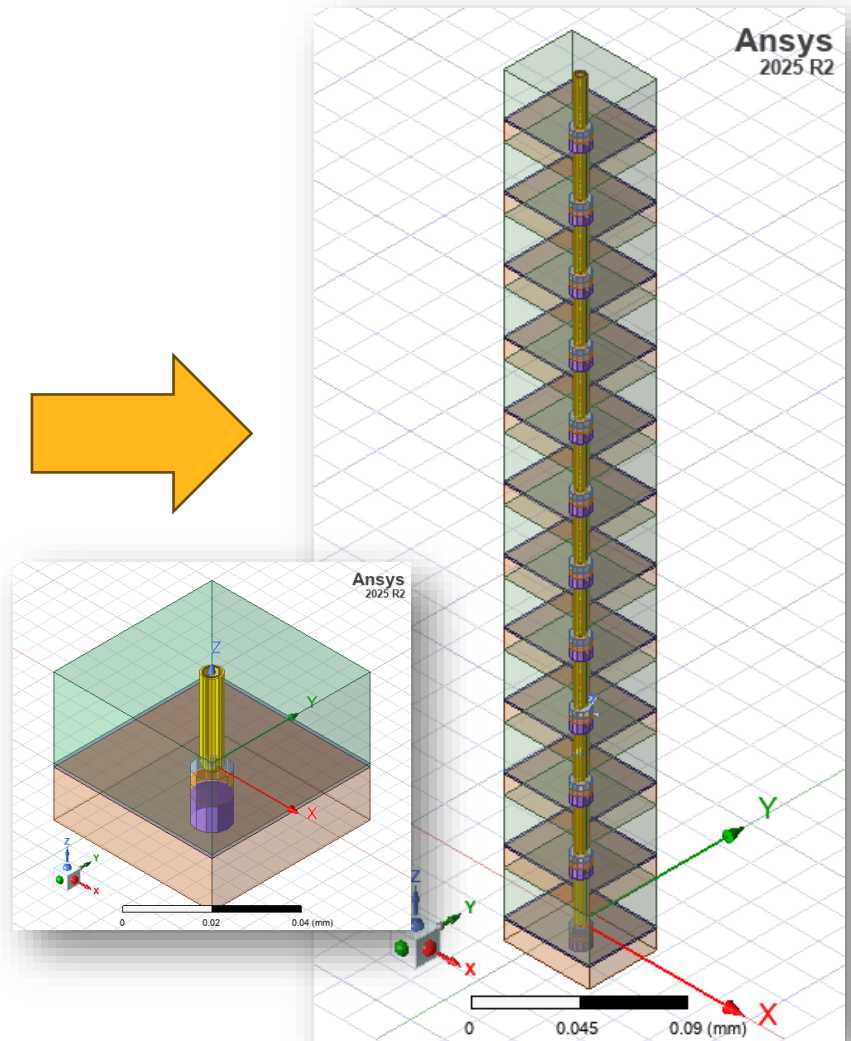
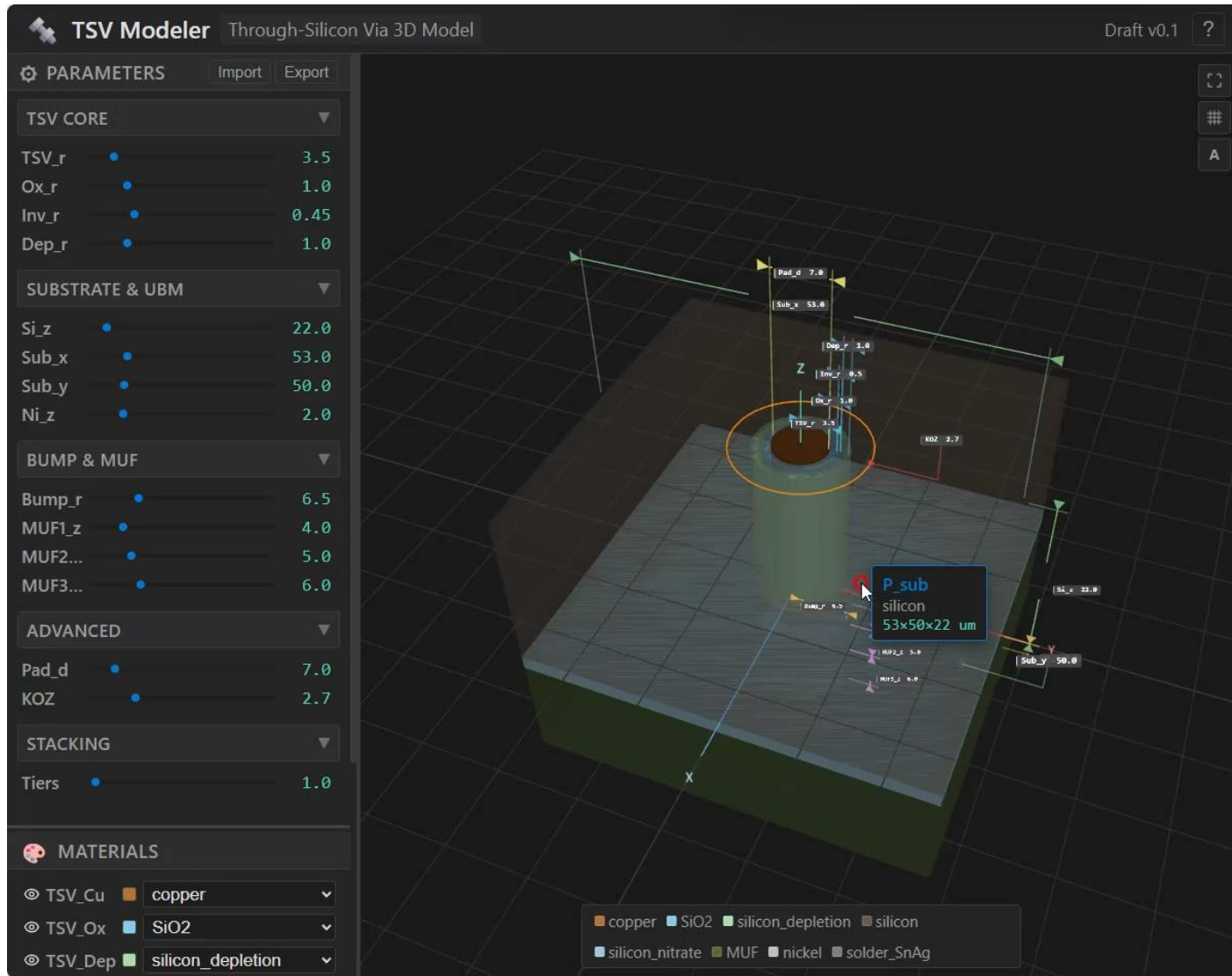
● Ground

- All Pin(TSV or Microbump) would be extracted as signal in Q3D
- Signal/Power/GND could be assigned to each TSV at circuit analysis to optimize it

Needs for automation

- **Non-GUI process**
 - Slow rendering due to complex 3D model like as 1000 TSVs
 - From pre-processing to analyze & post-processing
- **Array based on X,Y coordination data**
 - Microbump/TSVs should be located at arbitrary/proper position
- **RLC/SPICE reduction & export**
 - Huge size of SPICE/RLC from the bunch of terminal
 - Needs for RLC threshold control / reduce order

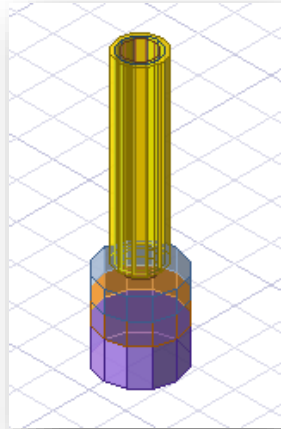
Automatic TSV modeling with variable



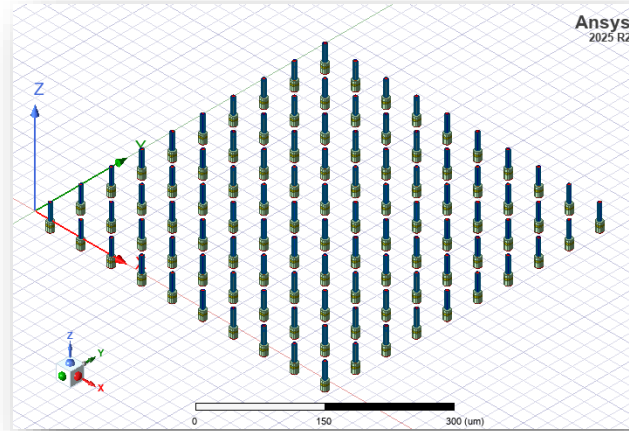
- Generate fully parameterized TSV model

Key Automation : TSV/uBump array based on X,Y coordinate data

Uniform

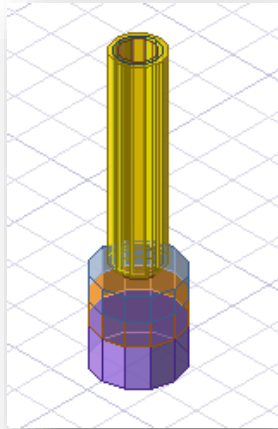


Manual duplicate

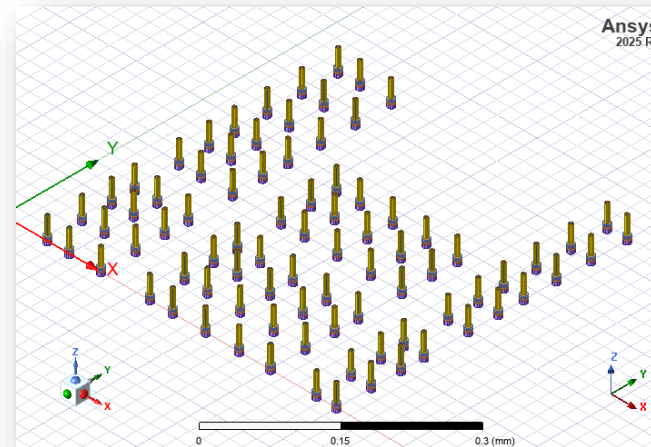


- Rectangular & uniform spacing

Arbitrary



Placement based on X,Y coordinate data



- Arbitrary shape & spacing

it's nearly impossible by manual due to..

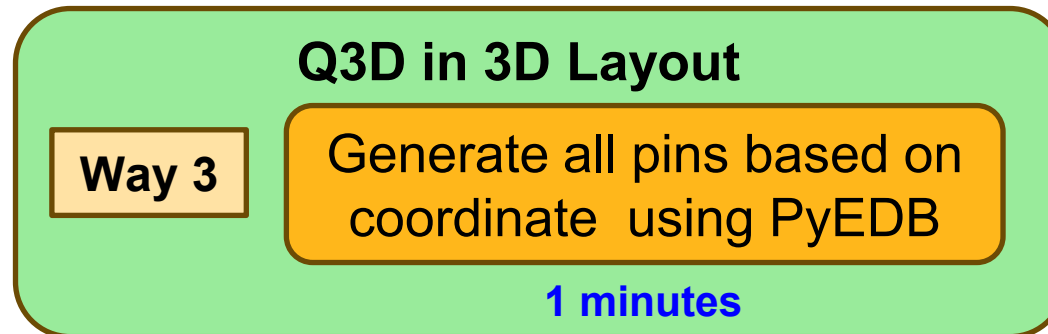
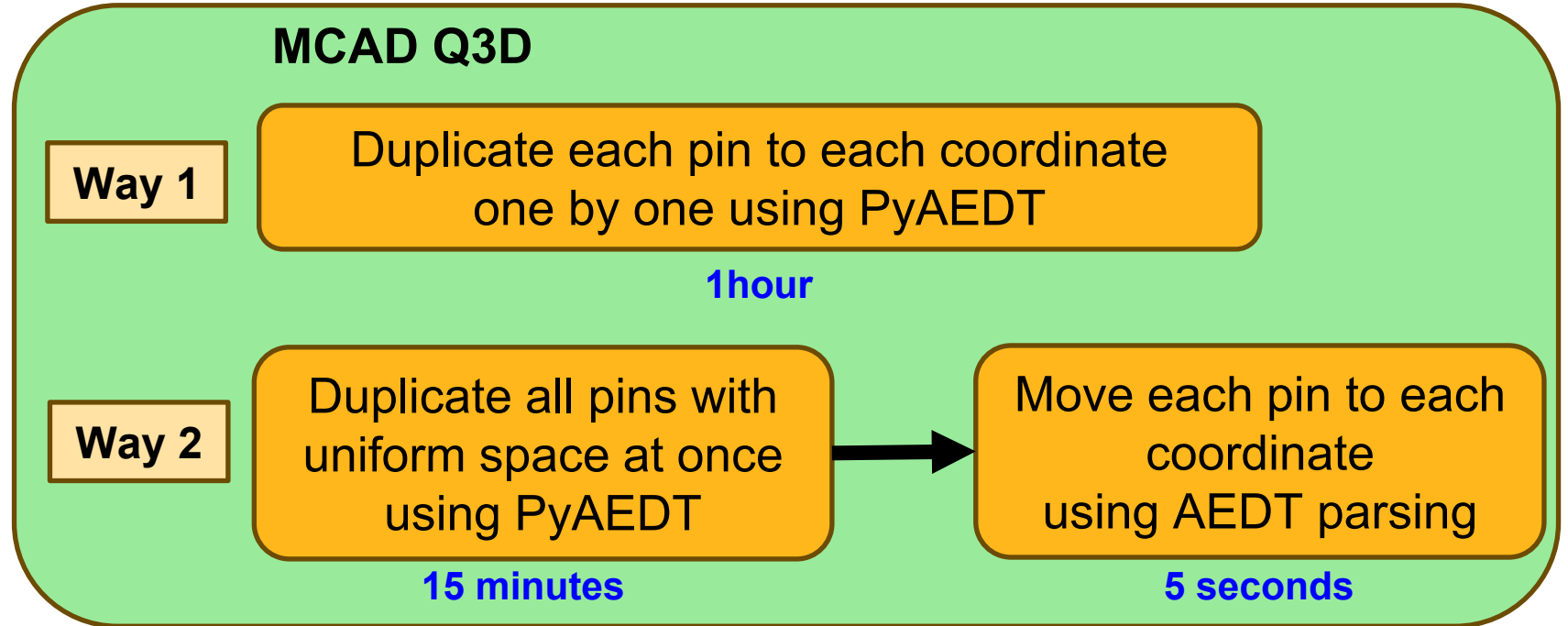
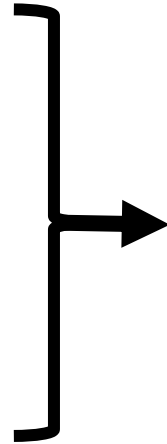
- too many TSVs
- slow GUI rendering
- extremely time consuming

Algorithm for pin array based on X,Y coordinate

* 1000 pins case example

Base model
(TSV / ubump)

X,Y coordinate
data

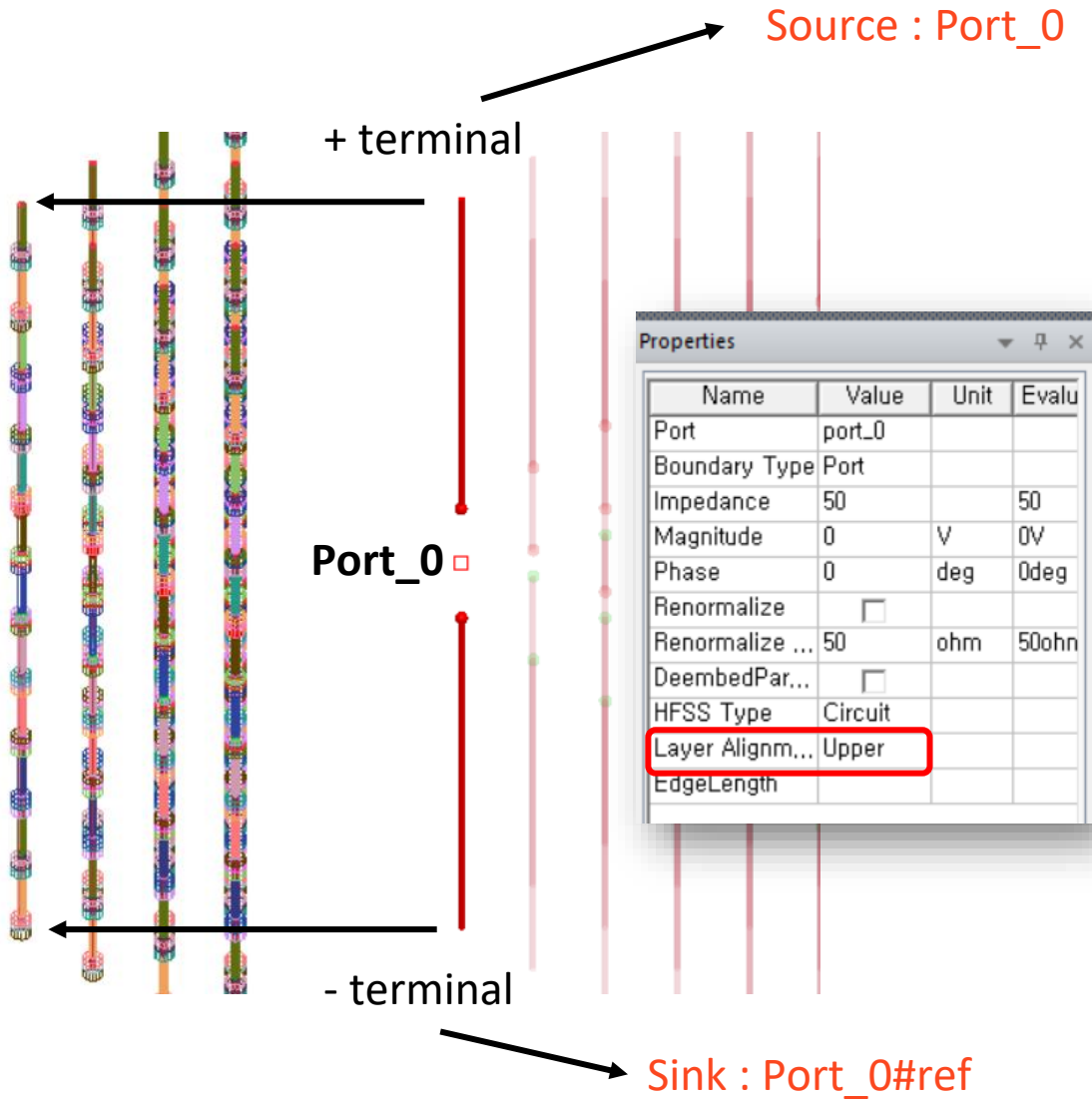


Automation : MCAD Q3D vs. Q3D in 3D Layout

	MCAD Q3D	Q3D in 3D Layout
Main API	PyAEDT	PyEDB
Automation speed	Slow (1~8hr)	Super fast (< 2m)
Net/terminal name change	easy	Complex
SPICE/RLC reduction	Use Internal function	Need for hard coding
Assign Source/sink	Easy & Simple	Depends on port property
Reduce matrix	Full function	Limited function

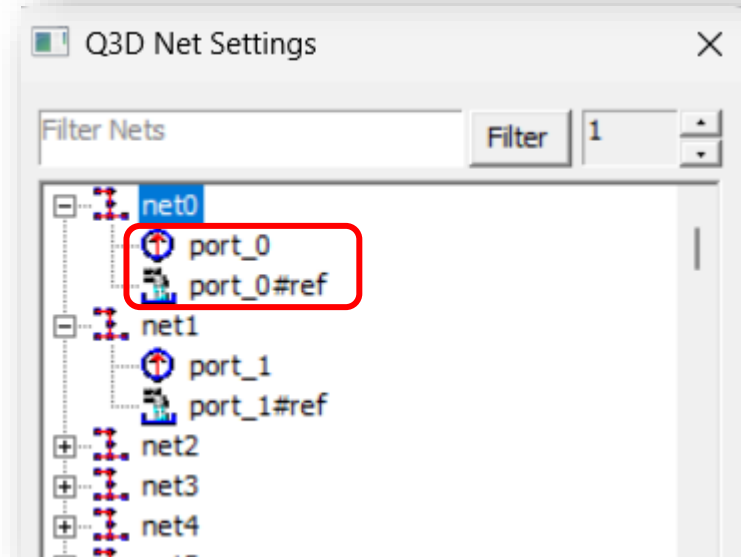
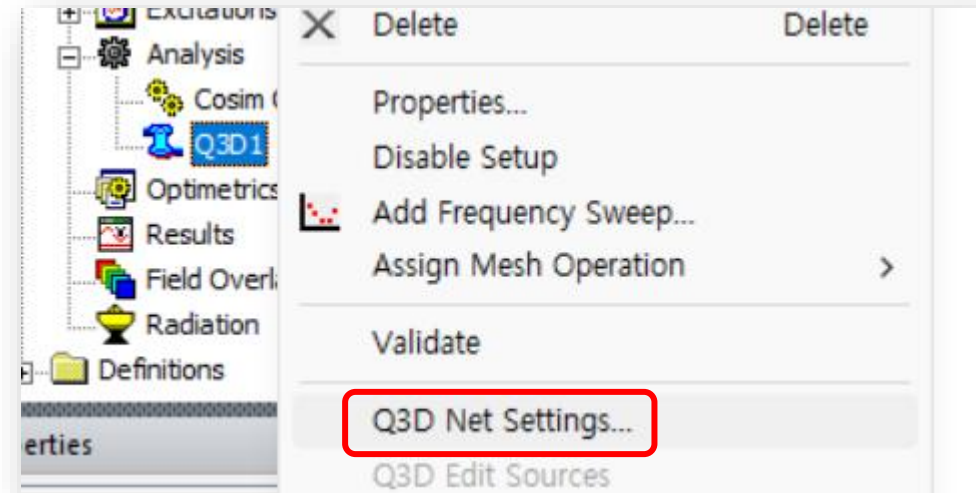


Tip for Q3D in 3D Layout : single circuit port Source & Sink

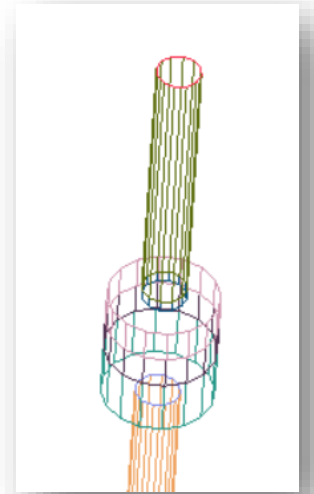
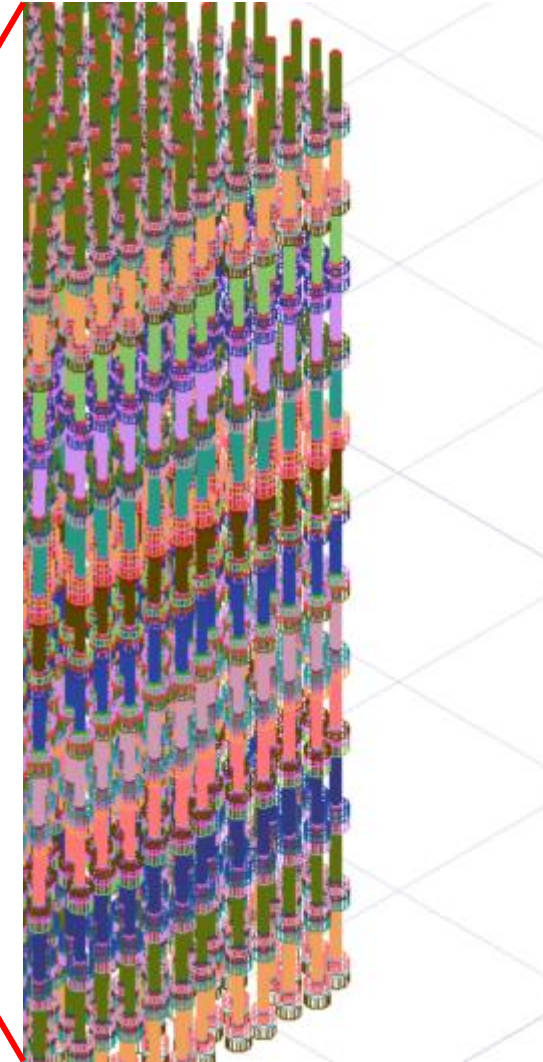
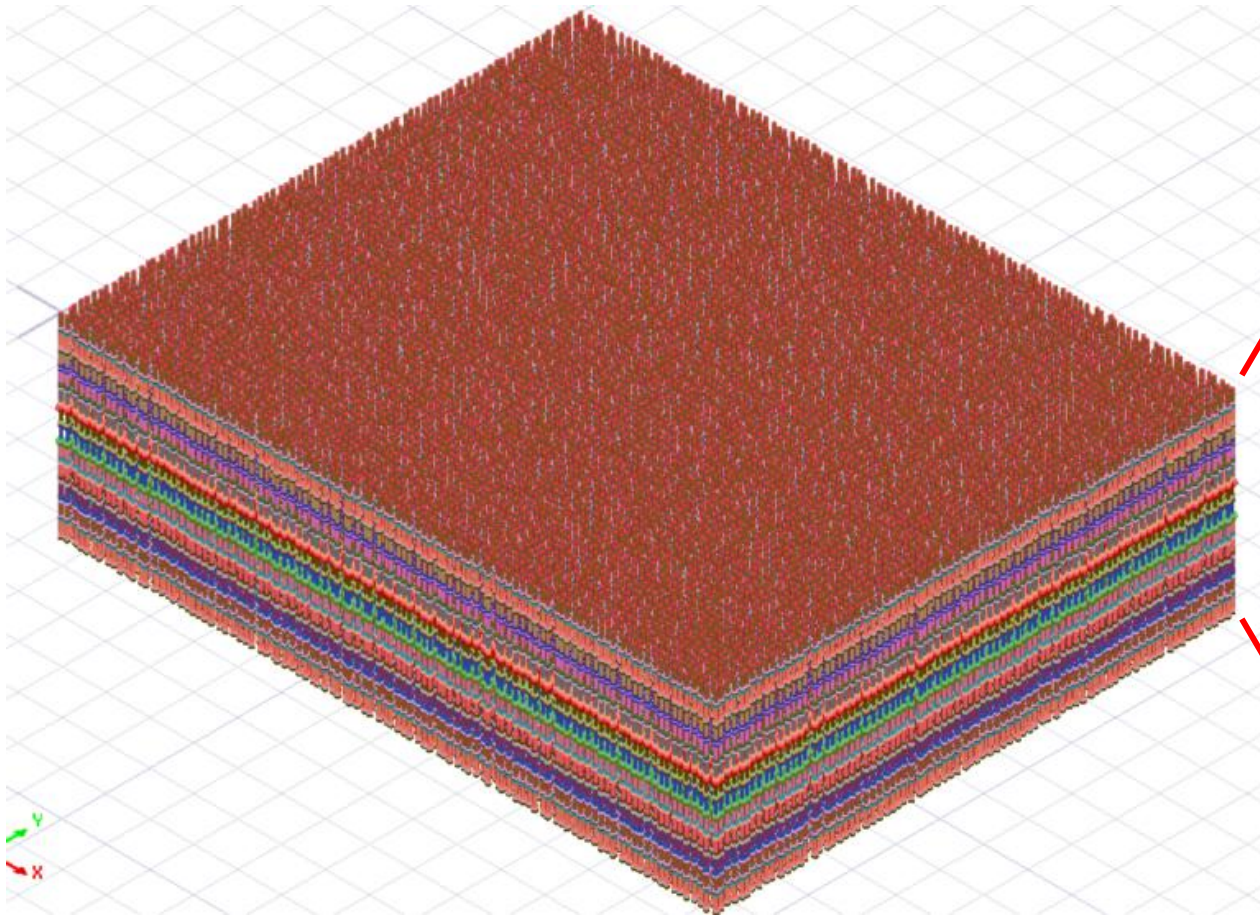


Properties

Name	Value	Unit	Evalu
Port	port_0		
Boundary Type	Port		
Impedance	50		50
Magnitude	0	V	0V
Phase	0	deg	0deg
Renormalize	<input type="checkbox"/>		
Renormalize ...	50	ohm	50ohm
DeembedPar...	<input type="checkbox"/>		
HFSS Type	Circuit		
Layer Alignm...	Upper		
EdgeLength			



3DL Q3D Automation Test (8000 ea with X,Y coordinate)



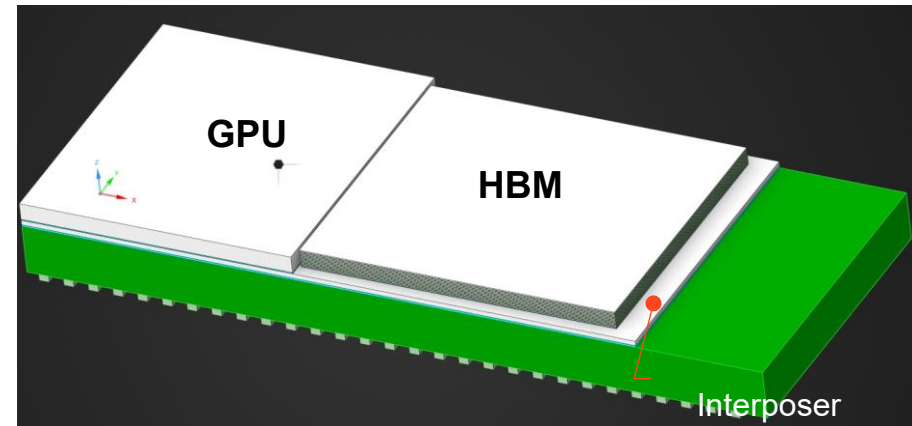
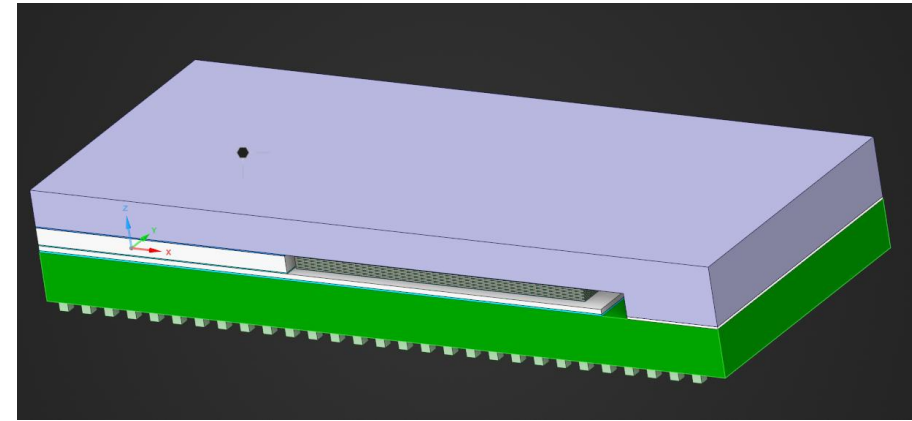
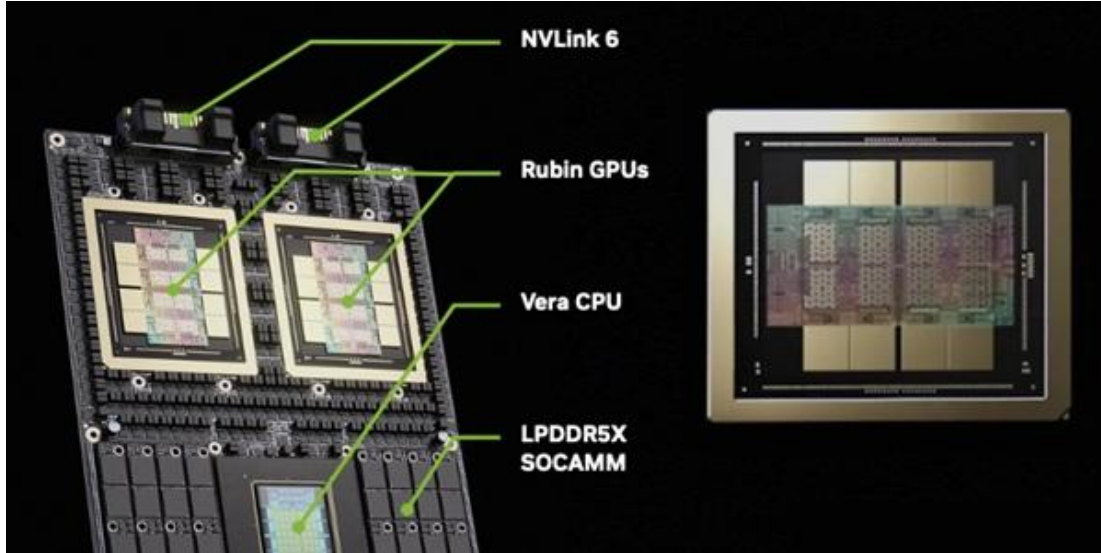
Duplicate using EDB : 2 minutes
open aedb : 3 minutes
AEDT fiel with aedb folder : 100MB



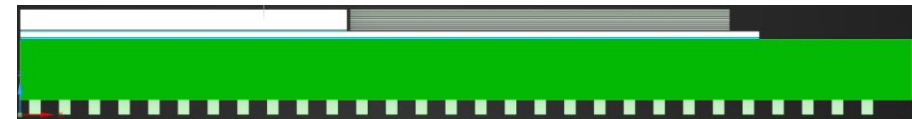


Microbump Thermal Simulation

Partial modeling of 2.5D package



Simulation Model →



HBM4 bump information

JESD270-4A

JEDEC Standard No. 270-4A
Page 202

11.2 MicroBump Positions

The MicroBump array of the DRAM stack employs a staggered pattern as depicted in Figure 104 where a "staggered" bump is located halfway between major row and column, hence its location is determined by $X/2$ and $Y/2$. Table 110 shows geometric parameters of the Staggered MicroBump pattern. Parameter P_{min} is the minimum bump pitch anywhere in the MicroBump field; for chosen X and Y parameters.

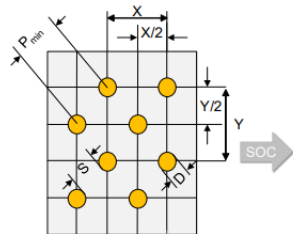


Figure 104 — Staggered MicroBump Pattern

Table 110 — Geometric Parameters of the Staggered MicroBump Pattern

Label	Nominal Value	Description
X	70 μm	Horizontal pitch of two adjacent MicroBumps
Y	110 μm	Vertical pitch of two adjacent MicroBumps
P_{min}	65 μm	Minimum pitch of the bump field
D	28 μm	MicroBump diameter
S		Bump-to-bump air gap; $S = P_{min} - D$

The HBM4 bump map is defined as shown in subsequent tables. Please refer to MO-362 for device dimensions.

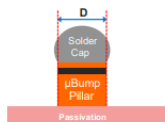


Figure 105 — MicroBump Pillar Diameter

Bump pitch: 65 μm

Bump diameter: 28 μm

Table 111 — HBM4 Device Dimensions

Parameter	Symbol	Configuration	Minimum	Nominal	Maximum	Unit	Notes
Width	X	24Gb/die	12.75	12.775	12.8	mm	3,4,5
		32Gb/die	14.15	14.175	14.2		
Length	Y		10.95	10.975	11	mm	
Height	Z	4-High	750	775	800	μm	1, 2
		8-High	750	775	800	μm	
		12-High	750	775	800	μm	
		16-High	750	775	800	μm	

NOTE 1 The configuration refers to the number of memory dies in the stack. The stack may include an additional base (interface) die.

NOTE 2 Refer to MO-362 for related package drawings.

NOTE 3 Refer to MO-362 for X and Y dimension min/Max tolerances and related package drawings.

NOTE 4 Refer to Footprint A in JESD271-4 "High Bandwidth Memory (HBM4) DRAM Bump Map Spreadsheet" for details on the 24 Gb/die footprint.

NOTE 5 Refer to Footprint B in JESD271-4 "High Bandwidth Memory (HBM4) DRAM Bump Map Spreadsheet" for details on the 32 Gb/die footprint.

HBM4 Package dimensions and bump layout

JESD271-4_HBM4_Ballout

Table 111 — HBM4 Device Dimensions

Parameter	Symbol	Configuration	Minimum	Nominal	Maximum	Unit	Notes
Width	X	24Gb/die	12.75	12.775	12.8	mm	3,4,5
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		8-High	750	775	800	μm	
		12-High	750	775	800	μm	
		16-High	750	775	800	μm	

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Bump map FootprintA

11.4 HBM4 Bump Map (cont'd)

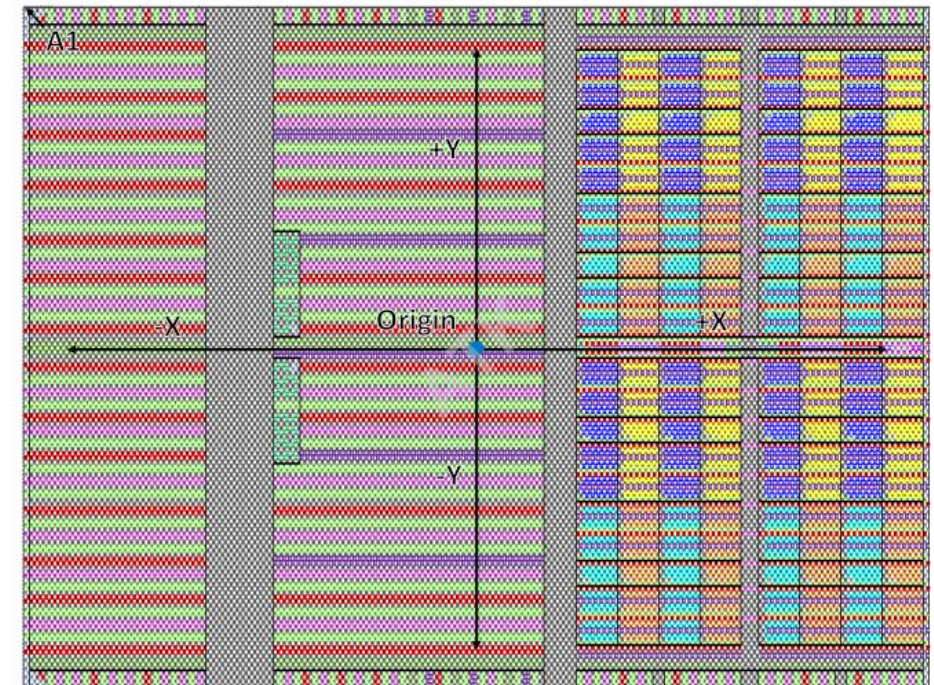
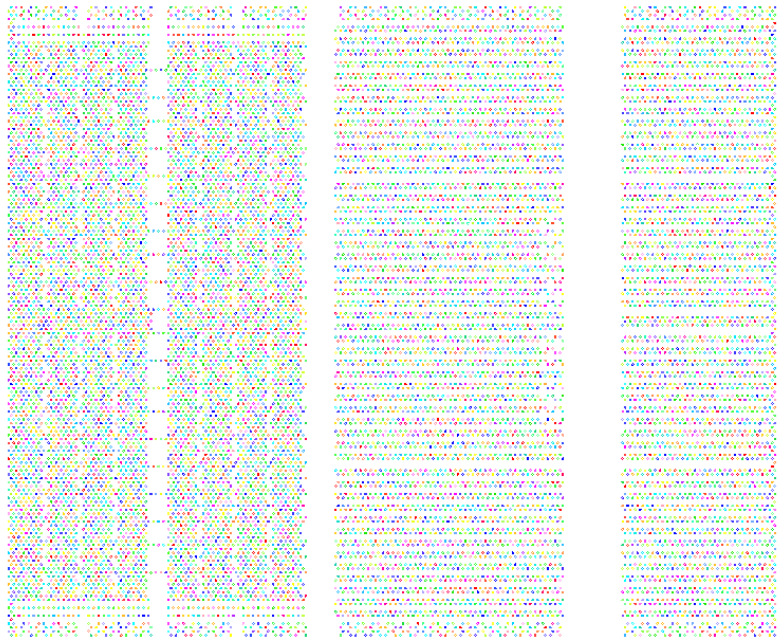
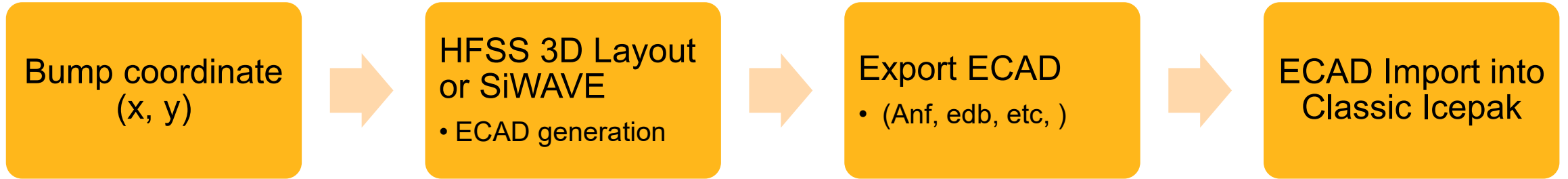
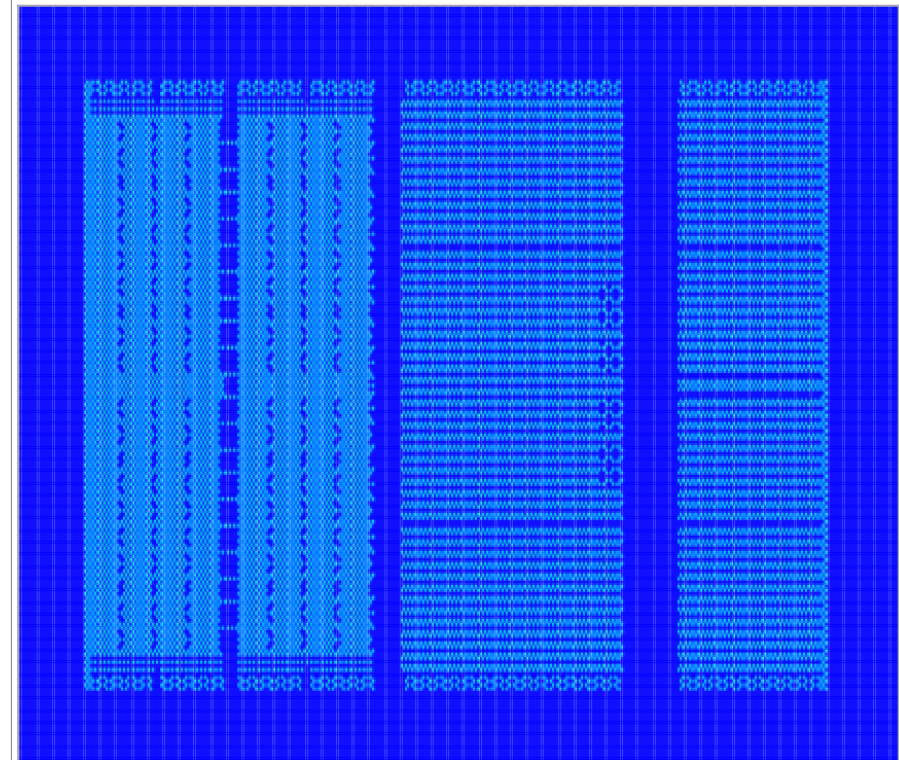
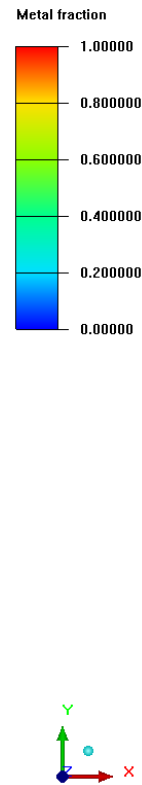


Figure 107 — Overview of HBM4 Bump Map Footprint A

ECAD import



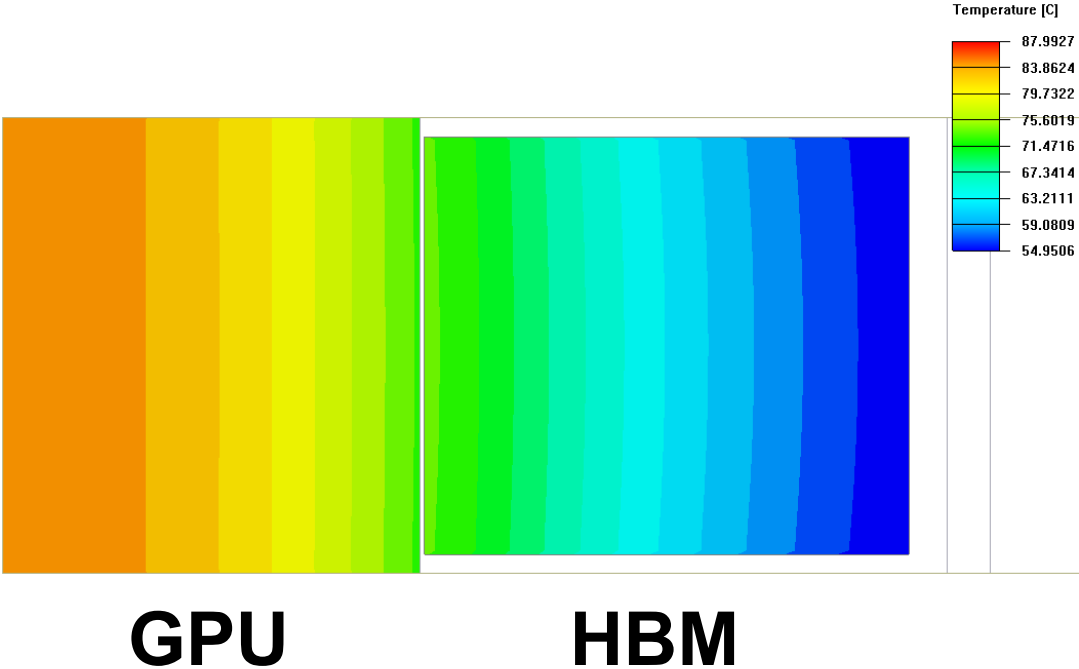
ECAD import



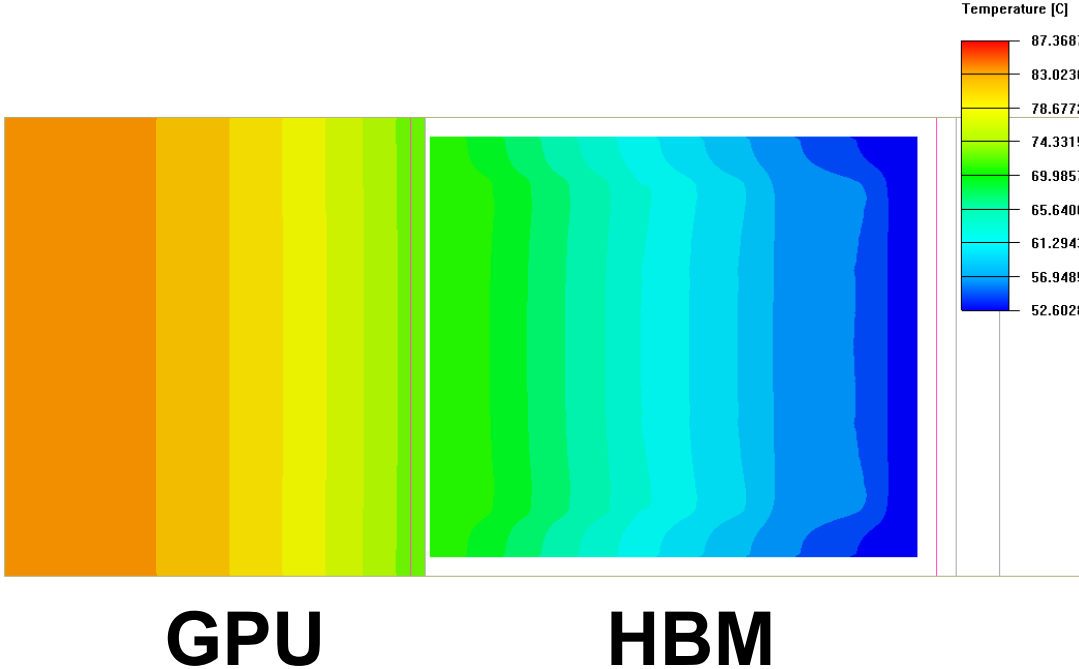
Metal fraction

Temperature contours on GPU and HBM dies

Lumped HBM bump

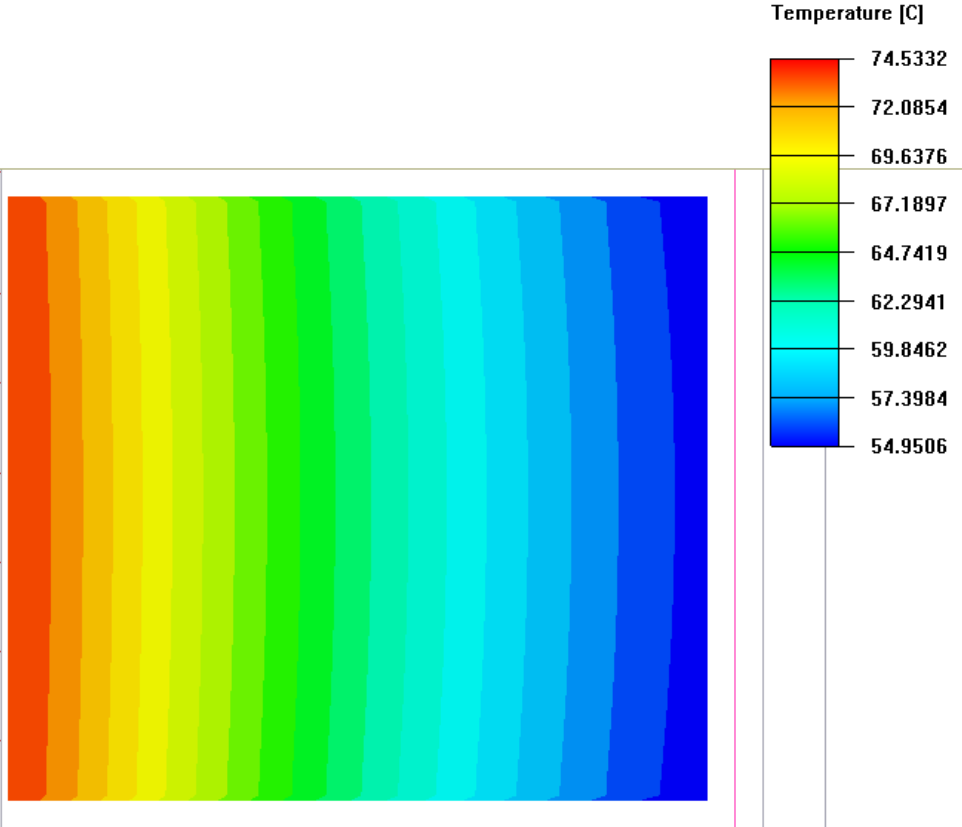


ECAD imported HBM bump (Real bump array based on coordinate)

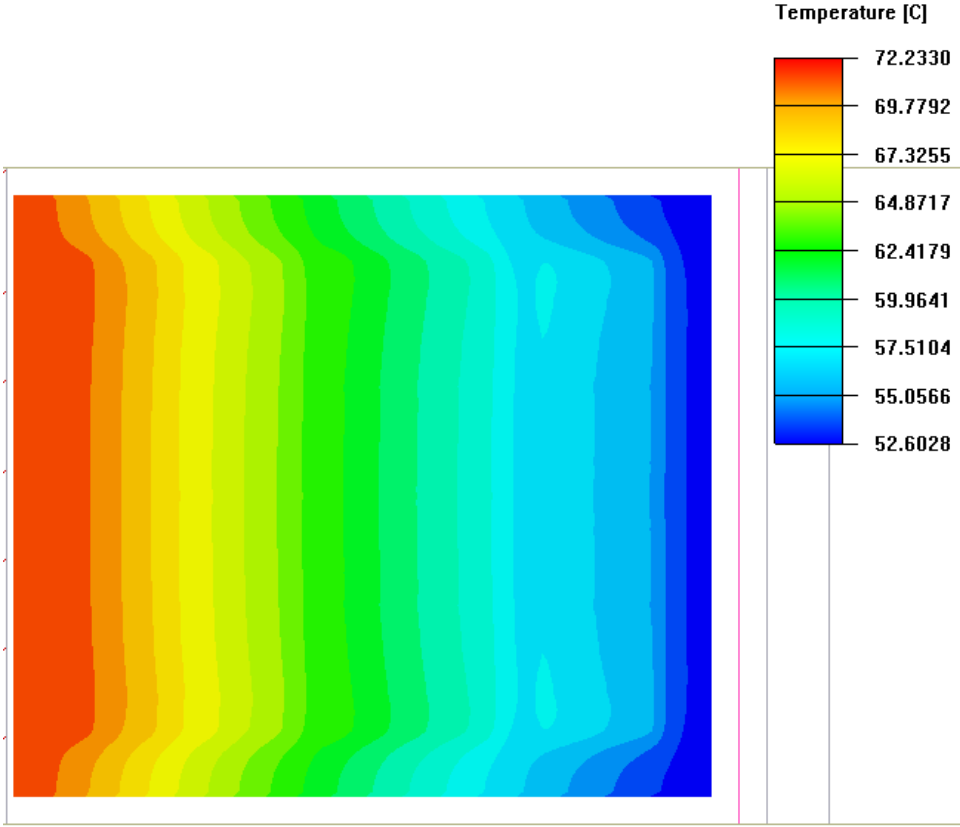


Temperature contours on HBM dies

Lumped HBM bump

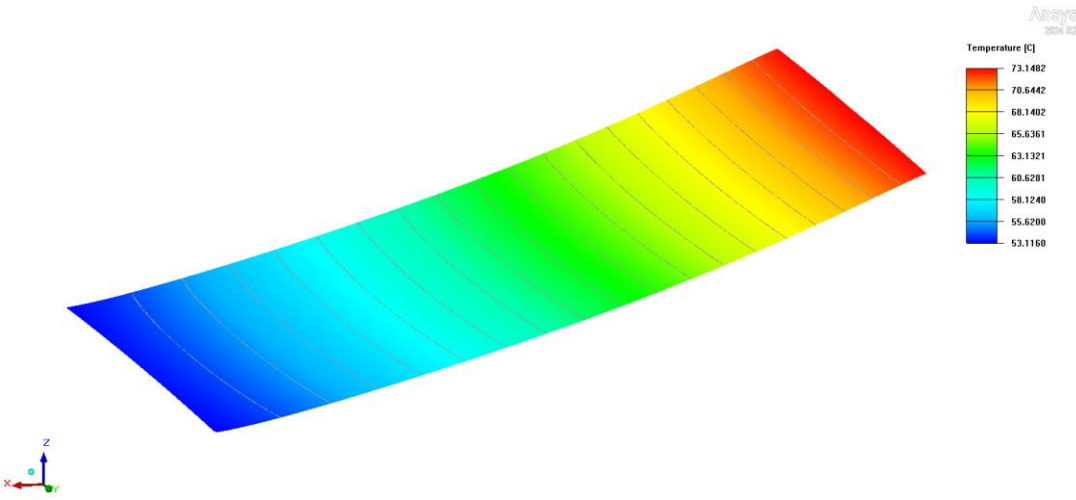


ECAD imported HBM bump (Real bump array based on coordinate)

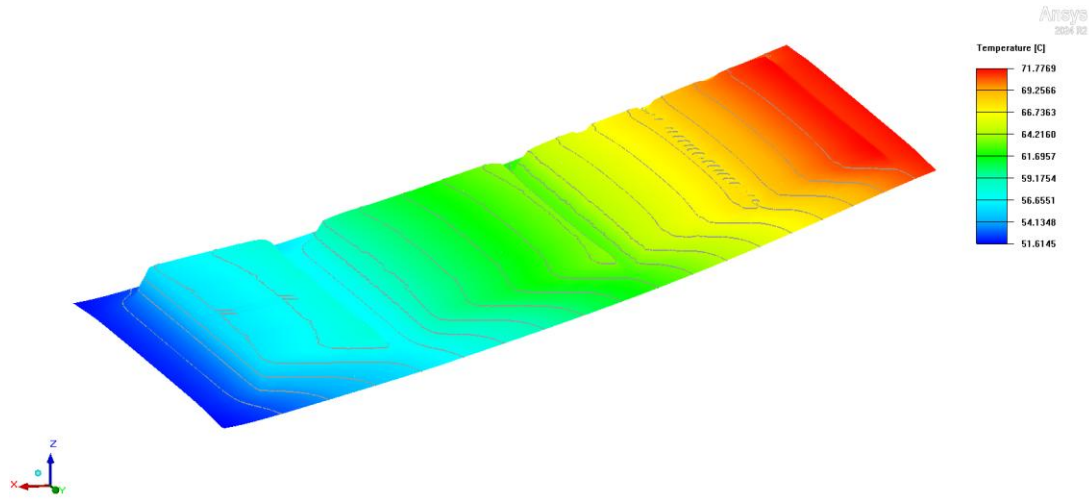


Temperature contours on HBM dies

Lumped HBM bump



ECAD imported HBM bump (Real bump array based on coordinate)



Conclusion

- **Q3D in 3D Layout can be advanced solution for HBM/3DIC application**
- **TSV parasitic analysis became a very important performance parameter for HBM design**
- **Need for automation for coordinate based TSV/Microbump design.**
- **Proper TSV/Microbump array should be designed based on coordinate for SI & Thermal performance**